





CDCI6214 SNAS734F - JULY 2017 - REVISED JANUARY 2024

CDCI6214 Ultra-Low Power Clock Generator With PCIe Support, Four Programmable **Outputs and EEPROM**

1 Features

- One configurable high performance, low-power PLL with four programmable outputs
- RMS jitter performance
 - Supports PCle Gen1/ Gen2 / Gen3 / Gen4 without SSC
- Typical power consumption: 150mW at 1.8V⁽²⁾
- Universal clock input
 - Differential AC-coupled or LVCMOS: 1MHz to 250MHz
 - Crvstal: 8MHz to 50MHz
- Flexible output frequencies
 - 44.1kHz to 350MHz
 - Glitchless output divider switching
- Four individually configurable outputs
 - LVCMOS, LVDS or HCSL
 - Differential AC-coupled with programmable swing (LVDS-, CML-, LVPECL-compatible)
- Fully integrated PLL, configurable loop bandwidth: 100kHz to 3MHz
- · Single or mixed supply operation for level translation: 1.8V, 2.5V and 3.3V
- Configurable GPIOs
 - Status signals
 - Up to four individual output enables
 - Output divider synchronization
- Flexible configuration options
 - I²C-compatible interface: up to 400kHz
 - Integrated EEPROM with two pages and external select pin
- Only supports 100Ω systems
- Industrial temperature range: -40°C to 85°C
- Small footprint: 24-pin VQFN (4mm × 4mm)

2 Applications

- PCIe Gen 1/2/3/4 clocking
- 1G / 10G Ethernet switches, NIC, accelerators
- Test & measurement, handheld equipment
- Multi-function printers
- Broadcast infrastructure

3 Description

The CDCI6214 device is an ultra-low power clock generator. The device selects between two independent reference inputs to a phase-locked loop and generates up to four different frequencies on configurable differential output channels and also a copy of the reference clock on a LVCMOS output channel.

Each of the four output channels has a configurable integer divider. Together with the output muxes, this allows up to five different frequencies. Clock distribution dividers are reset in a deterministic way for clean clock gating and glitch-less update capability. Flexible power-down options allow to optimize the device for lowest power consumption in active and standby operation. Typically four 156.25MHz LVDS outputs consume 150mW at 1.8V. Typical RMS litter of 386fs for 100MHz HCSL output enhances system margin for PCIe applications.

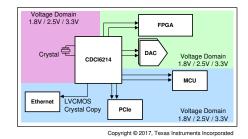
The CDCI6214 is configured using internal registers that are accessed by an I²C-compatible serial interface and internal EEPROM.

The CDCI6214 enables high-performance clock trees from a single reference at ultra-low power with a small footprint. The factory- and user-programmable EEPROM of the CDCI6214 is designed as an easyto-use, instant-on clocking feature with low power consumption.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽³⁾			
CDCI6214	RGE (VQFN, 24)	4.00mm × 4.00mm			

- For all available packages, see Section 13. (1)
- (2) Four LVDS outputs, 156.25MHz with crystal reference.
- The package size (length × width) is a nominal value and includes pins, where applicable.



Application Example CDCI6214



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4 Device Comparison

Table 4-1. Device Comparison

IDENTIFIER	REFERENCE INPUTS	ORDERABLE PART NUMBER	CHANNEL DIVIDER	CLOCK OUTPUTS	GENERAL- PURPOSE PINS	OUTPUT POWER SUPPLY PINS
CDCI6214	2	CDCI6214RGER	Integer	4 + 1	4	2
CDCl6214-Q1	2	CDCl6214TRGERQ1	Integer	4 + 1	4	2
CDCI6212	2	CDCI6212RGER	Integer	2 + 1	2	2

5 Pin Configuration and Functions

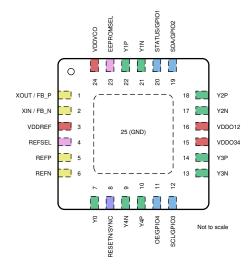


Figure 5-1. RGE Package 24-Pin VQFN Top View

Table 5-1. Pin Functions

PIN		TYPE	DESCRIPTION	
NAME	NO.	ITPE	DESCRIPTION	
XOUT/FB_P	1	Ю	Crystal Driver Output / LVCMOS Input / Differential Positive Reference	
XIN/FB_N	2	I	Crystal Input / Differential Negative Reference	
VDDREF	3	Р	Power Supply Pin for Input Path, Digital and EEPROM	
REFSEL	4	- 1	Manual Reference Selection MUX for PLL, R_{PU} = 50 k Ω , R_{PD} = 50 k Ω	
REFP	5	I	Differential Positive Reference	
REFN	6	I	Differential Negative Reference	
Y0	7	0	Output 0 Pin	
RESETN/SYNC	8	I	Chip Reset. Alternatively, Output Divider Sync, $R_{PU} = 50 \text{ k}\Omega^{(1)}$	
Y4N	9	0	Output 4 Negative Pin	
Y4P	10	0	Output 4 Positive Pin	
OE/GPIO4	11	Ю	Global output enable (default) or programmable GPIO, R_{PU} = 50 $k\Omega^{(1)}$	
SCL/GPIO3	12	Ю	Serial interface clock (default) or programmable GPIO	
Y3N	13	0	Output 3 Negative Pin	
Y3P	14	0	Output 3 Positive Pin	
VDDO34	15	Р	Power Supply for Outputs 3 and 4	
VDDO12	16	Р	Power Supply for Outputs 1 and 2	
Y2N	17	0	Output 2 Negative Pin	
Y2P	18	0	Output 2 Positive Pin	
SDA/GPIO2	19	Ю	Serial interface data (default) or programmable GPIO	

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Table 5-1. Pin Functions (continued)

PIN		TYPE	DESCRIPTION	
NAME	NO.	ITPE	DESCRIPTION	
STATUS/GPIO1	20	Ю	Status (default) or programmable GPIO, R_{PU} = 50 $k\Omega^{(1)}$	
Y1N	21	0	Output 1 Negative Pin	
Y1P	22	0	Output 1 Positive Pin	
EEPROMSEL	23	I	EEPROM Page Mode Select, R_{PU} = 50 k Ω , R_{PD} = 50 k $\Omega^{(1)}$	
VDDVCO	24	Р	Power Supply Pin for VCO / PLL	
GND	25	G	Ground, Thermal Pad	

(1) $\;\;$ R_{PU} is an internal pullup resistor. R_{PD} is an internal pulldown resistor.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
VDDREF, VDDVCO, VDDO12, VDDO34	Supply voltage	-0.3	3.65	V
XIN/FB_P, XOUT/FB_N, REFP, REFN	Input voltage	-0.3	VDDREF + 0.3	V
STATUS/GPIO1, SDA/GPIO2, SCL/GPIO3, OE/GPIO4, REFSEL, EEPROMSEL, RESETN/SYNC	Input voltage	-0.3	VDDREF + 0.3	V
Y0, Y1P, Y1N, Y2P, Y2N, Y3P, Y3N, Y4P, Y4N	Output voltage	-0.3	VDDO_x + 0.3	V
STATUS/GPIO1, SDA/GPIO2, SCL/GPIO3, OE/GPIO4	Output voltage	-0.3	VDDREF + 0.3	V
T _J	Junction temperature		125	°C
T _{stg}	Storage temperature		150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	2000	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	500	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
VDDREF, VDDVCO	Core supply voltage ⁽¹⁾	1.71	3.465	V
VDDO1	Output supply voltage	1.71	3.465	V
VDDO2	Output supply voltage	1.71	3.465	V
VDDO3	Output supply voltage	1.71	3.465	V
VDDO4	Output supply voltage	1.71	3.465	V
T _A	Ambient temperature	–40°C	85	°C

⁽¹⁾ VDDREF and VDDVCO must be powered from the same supply voltage.

6.4 Thermal Information

	THERMAL METRIC(1)		UNIT
	THERMAL METRIC	24 PINS	ONII
R _{θJA}	Junction-to-ambient thermal resistance	39.5	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	29.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	16.9	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	2.6	°C/W
ΨЈТ	Junction-to-top characterization parameter	0.4	°C/W

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



	THERMAL METRIC(1)	RGE (VQFN)	UNIT
	THERMAL METRIO	24 PINS	ONT
ΨЈВ	Junction-to-board characterization parameter	16.8	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the <u>Semiconductor and IC Package Thermal Metrics</u> application report.

6.5 EEPROM Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40°C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
n _{EEcyc}	EEPROM programming cycles	each word	10	10,000	cycles
t _{EEret}	EEPROM data retention		10		years

6.6 Reference Input, Single-Ended and Differential Mode Characteristics (REFP, REFN, FB_P, FB_N)

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and $T_A = -40$ °C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{IN_Ref}	Reference frequency		1		250	MHz
V _{IH}	Input high voltage	LVCMOS input buffer	0.8 × VDDREF			V
V _{IL}	Input low voltage	LVCMOS input buffer		,	0.2 × /DDREF	V
V _{IN_DIFF}	Differential input voltage swing, peak-to-peak	VDDREF = 2.5 V or 3.3 V, AC-coupled differential input buffer	0.5		1.6	V
V _{IN_DIFF}	Differential input voltage swing, peak-to-peak	VDDREF = 1.8 V, AC-coupled differential input buffer	0.5		1.0	V
dV _{IN} /dT	Input slew rate	20% – 80%	3			V/ns
IDC	Input duty cycle		40%		60%	
C _{IN_XOUT/FB_P}	Input capacitance	No xtal active, on-chip load disabled, at 25°C		7		pF
C _{IN_XIN/FB_P}	Input capacitance	No xtal active, on-chip load disabled, at 25°C		5		pF
C _{IN_REF}	Input capacitance	at 25°C		5		pF

6.7 Reference Input, Crystal Mode Characteristics (XIN, XOUT)

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and T_A = -40°C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{IN_Xtal}	Crystal frequency	Fundamental mode	8		50	MHz
Z _{ESR}	Crystal equivalent series resistance	A supported crystal is within	30		100	Ω
C _L	Crystal load capacitance	Using on-chip load capacitance. A supported crystal is within.	5		8	pF
P _{XTAL}	Crystal tolerated drive power	A supported crystal tolerates up to	100			uW
C _{XIN_LOAD}	On-Chip load capacitance	Programmable in typical 200- fF steps at room temp	3		9.1	pF
DNL _{XIN_LOAD}	Differential non-linearity	at room temp		200		fF

6.8 General-Purpose Input and Output Characteristics (GPIO[4:1], SYNC/RESETN)

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and T_A = -40° C to 85° C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{IH}	Input high voltage		0.8 × VDDREF			V

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40° C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{IL}	Input low voltage				0.2 × VDDREF	V
I _{IH}	Input high level current	VIH = VDDREF		-0.02		μA
I _{IH}	Input high level current	VIH = VDDREF, Pin 12, 19		0.004		μA
I _{IL}	Input low level current	VIL = GND		-50		μA
I _{IL}	Input low level current	VIL = GND, Pin 12, 19		-0.004		μA
dV _{IN} /dT	Input slew rate	20% – 80%	0.5			V/ns
C _{IN_GPIO}	Input Capacitance				10	pF
V _{OH}	Output high voltage	only capacitive load	0.8 × VDDREF			V
V _{OL}	Output low voltage	only capacitive load			0.2 × VDDREF	V
dV _{OUT} /dT	Output slew rate	20% - 80%, at 10pF		0.3		V/ns
R _{PU}	Pullup resistance	Pin 11, 20		77		kΩ

6.9 Triple Level Input Characteristics (EEPROMSEL, REFSEL)

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8V \pm 5%, 2.5V \pm 5%, 3.3V \pm 5% and T_A = -40° C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{IH}	Input high voltage		0.8 × VDDREF			V
V _{IM}	Input mid voltage		0.41 × VDDREF	0.5 × VDDREF	0.58 × VDDREF	V
V _{IL}	Input low voltage				0.2 × VDDREF	V
I _{IH}	Input high level current	VIH = VDDREF		40		μΑ
I _{IM}	Input mid level current	VIH = VDDREF/2		-1		μA
I _{IL}	Input low level current	VIL = GND		-40		μA
t _{RIN}	input slew rate	10% - 90%	50			ns
C _{IN_TRI}					10	pF
R _{PDPU}				64		kΩ

6.10 Reference Mux Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40° C to 85°C

	PARAMETER (1)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
L _{REF_MUX}	Reference mux isolation	XIN = Crystal 25 MHz, REF = 27 MHz		89		dBc
L _{REF_MUX}	Reference mux isolation	XIN = Crystal 25 MHz, REF = 24.576 MHz		78		dBc

⁽¹⁾ Mux isolation is defined as the attenuation relative to the carrier base harmonic as a positive dBc number.

6.11 Phase-Locked Loop Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and $T_A = -40^{\circ}$ C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT		
f _{PFD}	Phase detector frequency		1	100	MHz		
f _{VCO}	Voltage-controlled oscillator frequency		2400	2800	MHz		
f _{BW}	Configurable closed-loop PLL bandwidth	REF = 25 MHz	100	3000	kHz		

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40° C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{CLKDIST}	Clock distribution frequency		400		700	MHz
K _{VCO}	Voltage-controlled oscillator gain	f _{VCO} = 2.4 GHz		62		MHz/V
K _{VCO}	Voltage-controlled oscillator gain	f _{VCO} = 2.5 GHz		62		MHz/V
K _{VCO}	Voltage-controlled oscillator gain	f _{VCO} = 2.8 GHz		92		MHz/V
ΔT _{CL}	Allowable temperature drift for continuous lock	dT/dt ≤ 20 K / min			125	°C

6.12 Closed-Loop Output Jitter Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40° C to 85°C

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	int. Range from 10 kHz to 20 MHz , XIN = Crystal 25 MHz, Integer Output Divider, Yx = 156.25 MHz LVDS		500	750	fs
t _{RJ_CL} RMS phase jitter	int. Range from 10 kHz to 20 MHz , XIN = Crystal 25 MHz, Integer Output Divider, Yx = 100 MHz HCSL		386	800	fs
	PCIe Gen 3/4 Common Clock transfer functions applied, XIN = Crystal 25 MHz, Integer Output Divider, Yx = 100 MHz HCSL			500	fs

6.13 Output Mux Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40°C to 85°C

	PARAMETER (1)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
L _{OUT_MUX}	Output mux isolation	REF = 27 MHz, XIN = 25 MHz, VCO = 2500 MHz, PSFB = 4, Y_ODD = 312.5 MHz, Y_EVEN = 208.3 MHz, LVPECL		65		dBc
L _{OUT_MUX}	Output mux isolation	REF = 27 MHz, XIN = 25 MHz, VCO = 2500 MHz, PSFB = 4, Y_ODD = 312.5 MHz, Y_EVEN = 250 MHz, LVPECL		63		dBc
L _{OUT_MUX}	Output mux isolation	REF = 27 MHz, XIN = 25 MHz, VCO = 2500 MHz, PSFB = 4, Y_ODD = 312.5 MHz, Y_EVEN = 89.3 MHz, LVPECL		72		dBc
L _{OUT_MUX}	Output mux isolation	REF = 27 MHz, XIN = 25 MHz, VCO = 2500 MHz, PSFB = 4, IODs = 312.5 MHz, Yx=BYPASS (XIN), LVPECL		64		dBc
L _{OUT_MUX}	Output mux isolation	REF = 27 MHz, XIN = 25 MHz, VCO = 2500 MHz, PSFB = 4, Y_ODD = 100 MHz, Y_EVEN = 266.6 MHz, LVPECL		57		dBc

⁽¹⁾ Mux isolation is defined as the attenuation relative to the carrier base harmonic as a positive dBc number.

6.14 LVCMOS Output Characteristics

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VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and $T_A = -40$ °C to 85°C

100100,	VBBOIL, VBBOOI, VBBILLI I.	0 V _070, 2.0 V _070, 0.0 V _070 ui	14 1A 10 0 t	0 00 0		
	PARAMETER	TEST CONDITIONS	MIN	TYP MA	ιx	UNIT
f _{O_LVCMOS}	Output frequency	VDDO_x = 2.5 V or 3.3 V, normal drive	0.1	3	50	MHz
f _{O_LVCMOS}	Output frequency	VDDO_x = 1.8 V, normal drive	0.1	2	50	MHz

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and T_A = -40°C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
V _{OH_LVCMO}	Output high voltage	Normal mode, only capacitive load	0.8 × VDDREF		V
V _{OL_LVCMO}	Output low voltage	Normal mode, only capacitive load		0.2 × VDDREF	V
V _{OH_LVCMO}	Output high voltage	Slow mode, only capacitive load	0.7 × VDDREF		V
V _{OL_LVCMO}	Output low voltage	Slow mode, only capacitive load		0.3 × VDDREF	V
R _{ON_LVCMO} s	Output impedance	Normal mode		28	Ω
R _{ON_LVCMO}	Output impedance	Weak mode		80	Ω
L _{LVCMOS_10} 0M	Phase noise floor, single side band	f _{CARRIER} = 100 MHz, f _{OFFSET} = 10 MHz		-148	dBc/Hz

6.15 HCSL Output Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and $T_{\Delta} = -40^{\circ}$ C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{O_HCSL}	Output frequency		0.1		350	MHz
V _{CM_HCSL}	Output common mode		0.2	0.34	0.55	V
V _{OD}	Differential output voltage	f _{O_HCSL} = 100 MHz	0.4		1.0	V
V _{SS}	Differential output voltage, peak to peak	f _{O_HCSL} = 100 MHz	0.8		2.0	Vpp
V _{CROSS}	Absolute crossing point	$R_{\rm p}$ = 49.9 Ω ±5%, $f_{\rm O_HCSL}$ = 100 MHz	250		550	mV
ΔV _{CROSS}	Relative crossing point variation	w.r.t to average crossing point, f _{O_HCSL} = 100 MHz		100		mV
dV/dt	Slew rate for rising and falling edge	Differential, at V _{CROSS} ±150 mV, f _{O_HCSL} = 100 MHz ⁽¹⁾	1		4	V/ns
ΔdV/dt	Slew rate matching	Single-ended, at V _{CROSS} ±75 mV, f _{O_HCSL} = 100 MHz ⁽¹⁾			20%	
ODC	Output duty cycle	Not in PLL bypass mode	45%		55%	
R _P	Parallel termination	$R_p = 49.9 \Omega \pm 5\%$ required	45		55	Ω
L _{HCSL_100M}	Phase noise floor, single side band	f _{CARRIER} = 100 MHz, f _{OFFSET} = 10 MHz		-152		dBc/Hz

⁽¹⁾ PCIe test load slew rate

6.16 LVDS DC-Coupled Output Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and $T_{\Delta} = -40^{\circ}$ C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{O_PRG_AC}	Output frequency		0.1		350	MHz
V _{CM}	Output common mode	VDDO_X = 2.5 V, 3.3 V, chx_lvds_cmtrim_inc = 2	1.125	1.2	1.375	V
V _{CM}	Output common mode	VDDO_X = 1.8 V, chx_lvds_cmtrim_inc = 2	0.8 0.9		1	V
V _{OD}	Differential output voltage	LVDS	0.25	0.3	0.45	V
t _{RF}	Output rise/fall times	LVDS (20% to 80%)		675		ps
ODC	Output duty cycle	Not in PLL bypass mode	45%		55%	
L _{LVDS_DC_1}	Phase noise floor, single side band	f _{CARRIER} = 100MHz, f _{OFFSET} = 10MHz		-152		dBc/Hz



6.17 Programmable Differential AC-Coupled Output Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40°C to 85°C and AC-coupled outputs

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{O_PRG_AC}	Output frequency		0.1		350	MHz
V _{OD}	Differential output voltage	LVDS-like		0.45		V
V _{OD}	Differential output voltage	CML-like		0.8		V
V _{OD}	Differential output voltage	LVPECL-like		0.9		V
t _{RF}	Output rise/fall times	LVDS-like (20% to 80%)		675		ps
t _{RF}	Output rise/fall times	CML-like (20% to 80%)		520		ps
t _{RF}	Output rise/fall times	LVPECL-like (20% to 80%)		500		ps
ODC	Output duty cycle	Not in PLL bypass mode	45%		55%	
L _{DIFF_AC_10} 0M	Phase noise floor, single side band	f _{CARRIER} = 100 MHz, f _{OFFSET} = 10 MHz		-152		dBc/Hz

6.18 Output Skew and Delay Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and T_A = -40° C to 85° C

7							
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t _{SK_HCSL}	Skew between HCSL	$Y[4:1] = HCSL, f_{OY[4:1]} = 100 MHz$		140		ps	
t _{SK_DIFFAC}	Skew between progr. differential AC	Y[4:1] = programmable output swing, $f_{OY[4:1]}$ = 100 MHz		150		ps	
t _{SK_LVCMOS}	Skew between LVCMOS	Y[4:1] = LVCMOS, f _{OY[4:1]} = 100 MHz		100		ps	
t _{SK_LVCMOS} _BYP	Skew between LVCMOS to Bypass	Y[4:0] = LVCMOS, f _{OY[4:0]} = 100 MHz		3		ns	
t _{PD_ZDM}	Propagation delay	$\begin{aligned} &REF = 67 \;MHz, VCO = 2680 \\ &MHz, PSFB = 4, PSA_{Y_ODD} = 4, \\ &PSB_{Y_EVEN} = 4, IOD_{Y_ODD} = 10, \\ &IOD_{Y_EVEN} = 10, Y_{P_ODD} = Y_{N_ODD} \\ &= IOD, in \; ext. \; ZDM, LVCMOS \end{aligned}$	-600		600	ps	

6.19 Output Synchronization Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40° C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{SU_SYNC}	Setup time SYNC pulse	With respect to PLL reference rising edge at 100 MHz with R = 1	3			ns
t _{H_SYNC}	Hold time SYNC pulse	With respect to PLL reference rising edge at 100 MHz with R = 1			3	ns
t _{PWH_SYNC}	High pulse width for SYNC	With R = 1, at least 2 PFD periods + 24 feedback pre-scaler periods	60			ns
t _{PWL_SYNC}	Low pulse width for SYNC	With R = 1, at least 1 PFD period	6			ns
t _{EN}	Individual output enable time ⁽¹⁾	Tri-state to first rising edge, f _{Y[4:1]} < 200 MHz		4		nCK
t _{DIS}	Individual output disable time ⁽¹⁾	Last falling edge to tri-state, f _{Y[4:1]} < 200 MHz		4		nCK

⁽¹⁾ Output clock cycles of respective output channel. Global output enable handled by digital logic, additional propagation will be added.

6.20 Timing Characteristics

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and T_A = -40°C to 85°C

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
tivit Initialization time(3)	Initialization time from POR to device releasing PLL outputs.			5	ms

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40°C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{VDD}	Power supply ramp ⁽¹⁾ (2)	Timing requirement for any VDD pin while RESETN = LOW	50		2000	μs

- (1) RESETN pin should be LOW until VDD reaches 95% of final value. TI recommends adding a pullup resistor of 4.7 k Ω and a capacitance of 0.47 μ F to Ground on RESETN pin to meet the POR timing requirement.
- (2) After supply is settled within ±5% of target value, the initial rising edge on RESETN will start internal logic.
- (3) $t_{INIT} = t_{EELOAD} + t_{STAB}$

6.21 I²C-Compatible Serial Interface Characteristics (SDA/GPIO2, SCL/GPIO3)

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and $T_A = -40$ °C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
V _{IH}	Input voltage, logic high		0.7 × VDDREF		V
V _{IL}	Input voltage, logic low			0.3 × VDDREF	V
V _{HYS}	Input Schmitt trigger hysteresis	VDDREF = 3.3 V, f _{SCL} = 400 kHz	156		mV
V _{HYS}	Input Schmitt trigger hysteresis	VDDREF = 2.5 V, f _{SCL} = 400 kHz	118		mV
V _{HYS}	Input Schmitt trigger hysteresis	VDDREF = 1.8 V, f _{SCL} = 400 kHz	85		mV
I _{IH}	Input leakage current	VDDREF = 0.17 V3.12 V	-10	10	μA
V _{OL}	Low-level output voltage	At 3-mA sink current, VDDREF = 3.3 V – 5%		0.4	V
V _{OL}	Low-level output voltage	At 3-mA sink current, VDDREF = 2.5 V – 5%		0.4	V
V _{OL}	Low-level output voltage	At 2-mA sink current, VDDREF = 1.8 V – 5%		0.342	V
I _{OL}	Low-level output current	V _{OL} = 0.4 V	3		mA
C _{IN}	Input capacitance			10	pF

6.22 Timing Requirements, I²C-Compatible Serial Interface (SDA/GPIO2, SCL/GPIO3)

VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V \pm 5%, 2.5 V \pm 5%, 3.3 V \pm 5% and T_A = -40° C to 85°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PW_G}	Pulse width of suppressed glitches				50	ns
f _{SCL}	SCL clock frequency	Standard		100		kHz
f _{SCL}	SCL clock frequency	Fast-mode		400		kHz
t _{SU_STA}	Setup time start condition	SCL = V _{IH} before SDA = V _{IL}		0.6		μs
t _{H_STA}	Hold time start condition	SCL = V _{IL} after SCL = V _{IL} . After this time, the first clock edge is generated.		0.6		μs
t _{SU_SDA}	Setup time data	SDA valid after SCL = V _{IL} , f _{SCL} = 100 kHz	250			ns
t _{SU_SDA}	Setup time data	SDA valid after SCL = V _{IL} , f _{SCL} = 400 kHz	100			ns
t _{H_SDA}	Hold time data	SDA valid before SCL = V _{IH}	0			μs
t _{PWH_SCL}	Pulse width high, SCL	f _{SCL} = 100 kHz	4			μs
t _{PWH_SCL}	Pulse width high, SCL	f _{SCL} = 400 kHz	0.6			μs
t _{PWL_SCL}	Pulse width low, SCL	f _{SCL} = 100 kHz	4.7			μs
t _{PWL_SCL}	Pulse width low, SCL	f _{SCL} = 400 kHz	1.3			μs
t _{OF}	Output fall time	C _{OUT} = 10400 pF			250	ns



6.23 Power Supply Characteristics

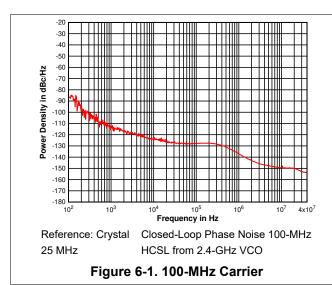
VDDVCO, VDDO12, VDDO34, VDDREF = 1.8 V $\pm 5\%$, 2.5 V $\pm 5\%$, 3.3 V $\pm 5\%$ and $T_A = -40$ °C to 85°C

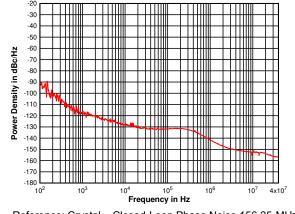
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I _{DD_REF}	Reference input current	DBL = on		4		mA
I _{DD_XIN}	Crystal input current	Crystal with P _{max} = 200 μW		2		mA
I _{DD_VCO}	VCO and PLL current	f_{VCO} = 2500 MHz, PSFB = PSA = 4 and PSB = off		13		mA
I _{DD_OUT}	Output channel current	Activated output channel, 1x LVDS 156.25 MHz		10		mA
I _{DD_IOD}	Output integer divider current			2		mA
I _{DD_PDN}	Power-down current	Using reset pin / bits		3		mA
I _{DD_TYP}	Typical current	4x 156.25-MHz LVDS case using crystal input and doubler		83		mA
L _{PSNR}	Power supply noise rejection ⁽¹⁾	Yx = 100 MHz LVDS, on one of VDDx injected sine wave 50 mV at f_{INJ} = 10 kHz,		-56		dBc
L _{PSNR}	Power supply noise rejection ⁽¹⁾	Yx = 100MHz LVDS, on one of VDDx injected sine wave 50 mV at f _{INJ} = 100 kHz		-46		dBc
L _{PSNR}	Power supply noise rejection ⁽¹⁾	Yx = 100MHz LVDS, on one of VDDx injected sine wave 50 mV at f _{INJ} = 1 MHz		-49		dBc
L _{PSNR}	Power supply noise rejection ⁽¹⁾	Yx = 100MHz LVDS, on one of VDDx injected sine wave 50 mV at f _{INJ} = 10 MHz		-69		dBc
L _{PSNR}	Power supply noise rejection ⁽¹⁾	Yx = 100MHz LVDS, on one of VDDx injected sine wave 50 mV at f _{INJ} = 20 MHz		-74		dBc
L _{PSNR}	Power supply noise rejection ⁽¹⁾	Yx = 100MHz LVDS, on one of VDDx injected sine wave 50 mV at f _{INJ} = 40 MHz		-73		dBc

(1) dBc with respect to output carrier frequency.

6.24 Typical Characteristics

VDDx = 1.8 V at room temperature





Reference: Crystal Closed-Loop Phase Noise 156.25-MHz
25 MHz LVDS from 2.5-GHz VCO

Figure 6-2. 156.25-MHz Carrier

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7 Parameter Measurement Information

7.1 Parameters

7.1.1 Reference Inputs

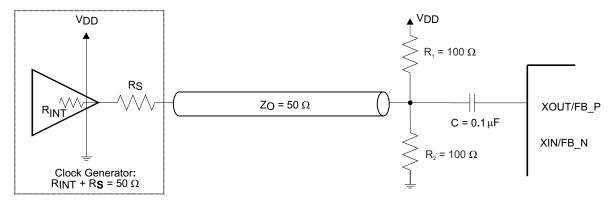
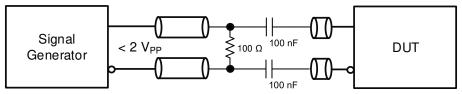


Figure 7-1. Single-Ended LVCMOS Crystal Input



A. Applied signal has to stay within $V_{\text{IN_DIFF}}$ limits.

Figure 7-2. Differential AC-Coupled Input

7.1.2 Outputs

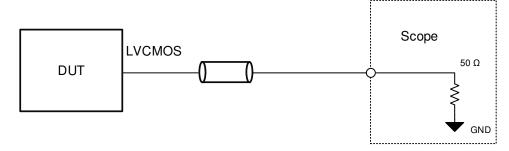


Figure 7-3. LVCMOS Output

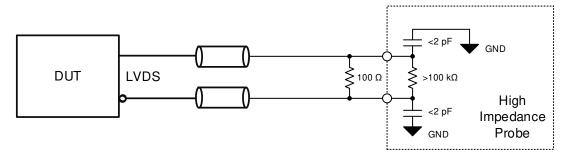


Figure 7-4. LVDS Output, DC-Coupled

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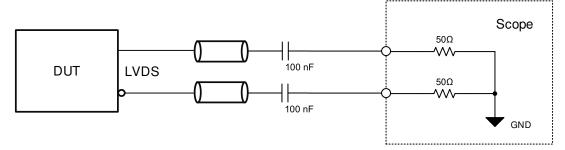


Figure 7-5. LVDS Output AC-Coupled

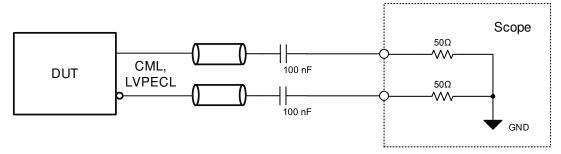


Figure 7-6. Differential AC-Coupled (CML, LVPECL)

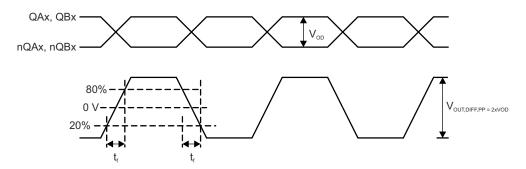
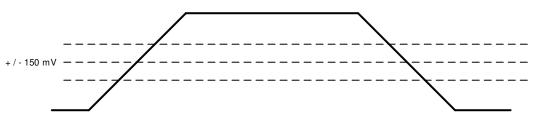


Figure 7-7. Differential Output Voltage and Rise/Fall Time

Differential Waveform HCSL



- A. Differential waveform created using math function in scope subtracting positive from negative output pin waveform: YxP YxN.
- B. Slew rate measured using absolute ± 150 mV on the differential waveform. This correlates to the cross-point of the single ended positive and negative waveform.

Figure 7-8. HCSL, Differential Rise and Fall Time



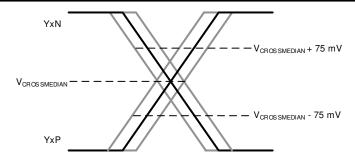
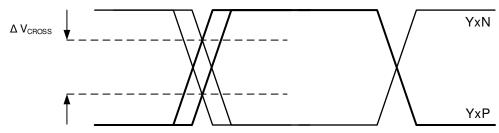


Figure 7-9. HCSL, Slew Rate Variation



A. Measurement conducted using the single ended waveforms. Total variation of the crossing point of rising YxP and falling YxN edges.

Figure 7-10. HCSL, Delta Crossing Voltage

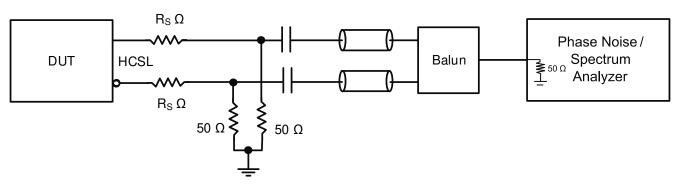
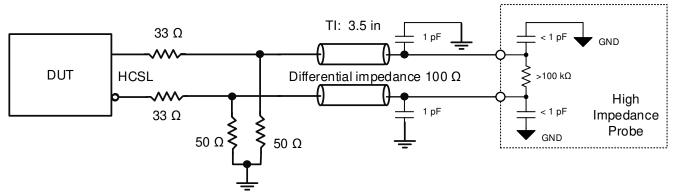


Figure 7-11. HCSL, Phase Noise Measurement



A. Measured using Tektronix DPO75902SX oscilloscope. Recommended to use an oscilloscope bandwidth setting of 4/8 GHz and vertical setting of 50mV/division. Data processed using Clock Jitter Tool: Ver:1.6.7.2.

Figure 7-12. HCSL PCIe Test Load Setup



7.1.3 Serial Interface

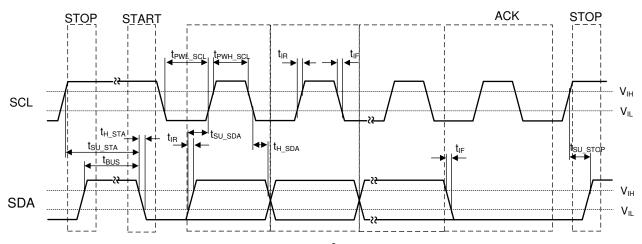


Figure 7-13. I²C Timing

7.1.4 Power Supply

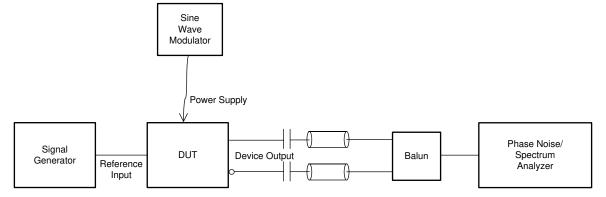


Figure 7-14. PSNR Setup

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8 Detailed Description

8.1 Overview

The CDCl6214 clock generator is a phase-locked loop with integrated loop filter and selectable input reference. The output of the integrated voltage-controlled oscillator (VCO) is connected to a clock distribution network, which includes multiple frequency dividers and feeds four output channels with configurable differential and single-ended output buffers.

8.2 Functional Block Diagram

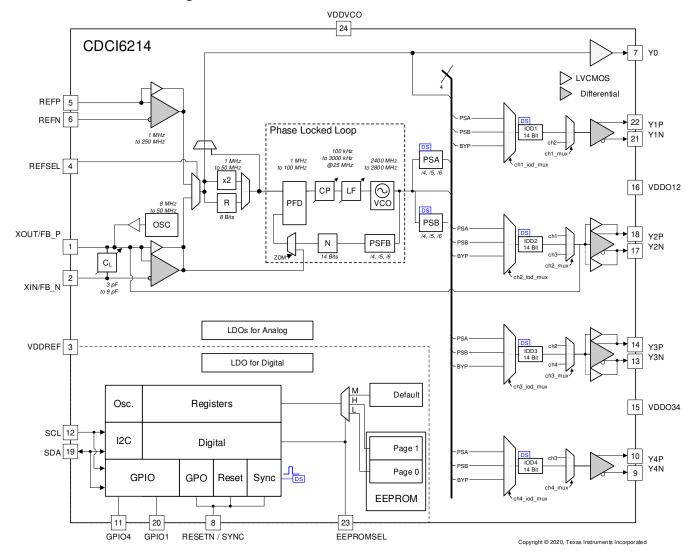


Figure 8-1. CDCI6214 Clock Generator With Four Outputs

8.3 Feature Description

The following sections describe the individual blocks of the CDCl6214 ultra-low power clock generator.

8.3.1 Reference Block

A reference clock to the PLL is fed to pins 1 (XOUT/FB P) and 2 (XIN/FB N) or to pins 5 (REFP) and 6 (REFN). There are multiple input stages available to adapt to many clock references. The bit-field that controls the reference input type selection is xin inbuf ctrl.

The reference mux selects the reference for the PLL and the PLL-bypass path. For debug purposes ip byp mux allows to connect the reference divider or doubler output to the clock distribution.

The buffers for the PLL-bypass path can be individually enabled and disabled using ip byp en ch[4:1] and ip_byp_en_y0.

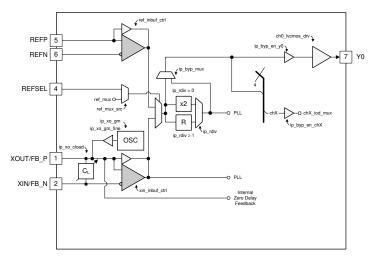


Figure 8-2. Reference Block

8.3.1.1 Input Stages

8.3.1.1.1 Crystal Oscillator

The XIN and XOUT pins provide a crystal oscillator stage to drive a fundamental mode crystal in the range of 8 MHz to 50 MHz. The crystal input stage integrates a tunable load capacitor array up to 9 pF using ip xo cload. The drive capability of the oscillator is adjusted using ip xo gm.

8.3.1.1.2 LVCMOS

The LVCMOS input buffer threshold voltage follows VDDREF. This helps to use the device as a level shifter as the outputs have separate supplies.

8.3.1.1.3 Differential AC-Coupled

The differential input stage has an internal bias generator and should only be used with AC-coupled reference inputs.

8.3.1.2 Reference Mux

Either XIN or REF can be selected as reference to the PLL and clock distribution path. The reference mux is controlled using the REFSEL pin with ref mux src or the ref mux bit-field with ref mux src.

8.3.1.3 Reference Divider

A reference divider can be used to divide higher input frequencies to the permitted PFD range. It supports division values of 1 to 255 using ip rdiv.

8.3.1.3.1 Doubler

The reference path contains a doubler circuit. It is used to double the input frequency and can be used to achieve the highest PFD update frequency of 100 MHz using a 50-MHz crystal. The doubler activates using ip rdiv = 0.

8.3.1.4 Bypass-Mux

The input reference or the input to the PFD can be routed to the bypass path using ip byp mux.

8.3.1.5 Zero Delay, Internal and External Path

In zero delay mode the REF input clock is used as reference clock at the PFD. The FB_P clock (LVCMOS) or FB_P/N clock (differential) can be used to feed an external source as feedback clock to the PFD. The external feedback path is recommended for zero delay operation. Moreover there is an additional internal feedback path which is sourced by output channel 2.

rable of the end of th												
		Reference						Feed	back			
REFSEL	ref_mux	ref_mux_s rc	ip_rdiv	ref_inbuf_ ctrl	xin_inbuf_ ctrl	zdm_mod e	zdm_clock sel	zdm_auto	pll_psfb	#none# pll_psa	pll_ndiv	ch2_iod_d iv (2)
L	х	0	1	х	0	0	x	х	х	x	х	x
Н	х	0	1	х	х	0	х	х	х	х	х	х
х	1	1	1	х	х	0	х	х	х	х	х	х
х	1	1	1	А	Α	1	0	1	В	В	С	С
х	1	1	1	А	Α	1	1	1	В	В	С	С
	L H x	L x H x x 1 x 1	REFSEL ref_mux ref_mux_s rc L x 0 H x 0 x 1 1 x 1 1	Reference REFSEL ref_mux ref_mux_s ref_mux_s ref_mux_s ip_rdiv L x 0 1 H x 0 1 x 1 1 1 x 1 1 1	Reference REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ctrl L x 0 1 x H x 0 1 x x 1 1 1 x x 1 1 1 A	Reference REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ ctrl xin_inbuf_ ctrl L X 0 1 X 0 H X 0 1 X X X 1 1 1 X X X 1 1 1 A A	Reference REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ctrl xin_inbuf_ctrl zdm_mod e L X 0 1 X 0 0 H X 0 1 X X 0 X 1 1 1 X X 0 X 1 1 1 A A 1	Reference REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ ctrl xin_inbuf_ zdm_mod zdm_clock sel L x 0 1 x 0 0 x H x 0 1 x x 0 x x 1 1 1 x x 0 x x 1 1 1 A A 1 0	Reference Feed REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ ctrl xin_inbuf_ zdm_mod e zdm_clock sel zdm_auto L X 0 1 X 0 0 X X H X 0 1 X X 0 X X X 1 1 1 X X 0 X X X 1 1 1 A A 1 0 1	Reference Feedback REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ctrl xin_inbuf_zdm_mod zdm_clock zdm_auto pll_psfb L X 0 1 X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X X <td>Reference Feedback REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ ctrl zdm_mod zdm_clock sel zdm_auto pll_psfb #none# pll_psa L X 0 1 X 0 X X X X H X 0 1 X X 0 X X X X X 1 1 1 X X 0 X X X X X 1 1 1 A A 1 0 1 B B</td> <td>Reference Feedback REFSEL ref_mux ref_mux_s rc ip_rdiv ref_inbuf_ctrl xin_inbuf_ctrl zdm_mod zdm_clock sel zdm_auto pll_psfb #none# pll_psa pll_ndiv L x 0 1 x 0 x x x x x H x 0 1 x x 0 x x x x x x 1 1 1 x x 0 x x x x x x 1 1 1 A A 1 0 1 B B C</td>	Reference Feedback REFSEL ref_mux ref_mux_s ip_rdiv ref_inbuf_ ctrl zdm_mod zdm_clock sel zdm_auto pll_psfb #none# pll_psa L X 0 1 X 0 X X X X H X 0 1 X X 0 X X X X X 1 1 1 X X 0 X X X X X 1 1 1 A A 1 0 1 B B	Reference Feedback REFSEL ref_mux ref_mux_s rc ip_rdiv ref_inbuf_ctrl xin_inbuf_ctrl zdm_mod zdm_clock sel zdm_auto pll_psfb #none# pll_psa pll_ndiv L x 0 1 x 0 x x x x x H x 0 1 x x 0 x x x x x x 1 1 1 x x 0 x x x x x x 1 1 1 A A 1 0 1 B B C

Table 8-1. Zero Delay Operation

8.3.2 Phase-Locked Loop

The CDCI6214 contains a fully integrated phase-locked loop circuit. The error between a reference phase and an internal feedback phase is compared at the phase-frequency-detector. The comparison result is fed to a charge pump that is connected to an integrated loop filter. The control voltage resulting from the loop filter tunes an internal voltage-controlled oscillator (VCO). The frequency of the VCO is fed through a pre-scaler feedback divider (PSFB) and another feedback divider back to the PFD.

The PLL closed-loop bandwidth is configurable using registers PLL0, PLL1, and PLL2.

- Integer PLL
- PFD operates 1 MHz to 100 MHz
- Live Lock-Detector provides PLL lock status on status pin and bit lock_det (there is an additional sticky bit unlock_s)
- Integrated selectable loop filter components
- For 25-MHz PFD bandwidths between 100 kHz and 3000 kHz can be achieved to optimize PLL to input reference
- Voltage-Controlled Oscillator (VCO) tuning range of 2400 to 2800 MHz
- VCO is compatible to 0.5% spread spectrum (SSC) references at 100 MHz.

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^{(1) &#}x27;x' allows any possible bit-field value. An entry of 'A', 'B' or 'C' indicates the same bit-field value.

⁽²⁾ For internal feedback channel 2 is required. For external feedback the output clock connected to FB_P/N is recommended to have same settings as default PLL feedback path.

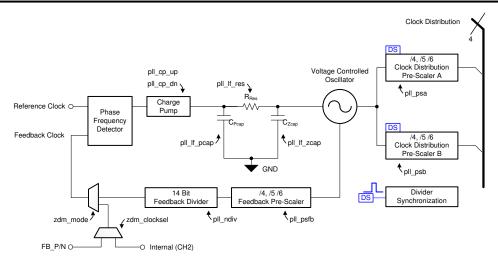


Figure 8-3. Phase-Locked Loop Circuit

Table 8-2.	Common	Clock Generator	Loop Filter Settings
-------------------	--------	------------------------	-----------------------------

f _{vco} in	f _{PFD} in MHz	BW in MHz	Phase	Damping	I _{CP} in mA	C _{Pcap} IN pF	R _{Res} IN kΩ	C _{Zcap} IN pF		
MHz ⁽¹⁾	IPFD III WII IZ	DW III WIIIZ	Margin in °	Factor	pll_cp_up (2)	pll_lf_pcap	pll_lf_res	pll_lf_zcap		
2400	25	0.51	67	0.9	2.0	17.5	2.5	450		
2400	50	0.97	67	1.3	2.0	17.5	2.5	450		
2400	100	1.41	68	1.2	2.4	17.5	1.5	450		
2457.6	61.44	1.04	67	1.4	1.8	17.5	2.5	450		
2500	25	0.49	67	0.9	2.0	17.5	2.5	450		
2500	50	0.93	68	1.3	2.0	17.5	2.5	450		
2680	67	0.38	67	1.3	0.2	19.5	5.5	480		
2688	48	0.93	68	1.3	1.5	17.5	2.5	480		
2688	96	0.36	67	1.0	0.2	19.5	3.5	480		
2800	50	1.00	68	1.0	2.6	17.5	1.5	450		
2800	100	1.00	68	1.0	1.3	17.5	1.5	450		

- All values typical design targets.
- Program same value to pll cp dn.

8.3.3 Clock Distribution

The VCO connects to two individually configurable pre-scaler dividers sourcing the on-chip clock distribution.

The clock distribution consists of four output channels. Each output channel contains a divider with integer division and synchronization capabilities.

A mux after each divider allows to feed the generated frequency to the adjacent output buffers. Thus for single frequency clock generation only a single output divider needs to be active.

The output buffers are compatible to various signaling standards: LVDS, CML-like, LVPECL-like, LVCMOS and HCSL using ch1 outbuf ctrl.

- HCSL must be directly connected to a load termination to ground. A series resistance can be used to adapt to the trace impedance.
- LVDS requires a differential termination connected between the positive and negative output buffer pins. The termination can be connected directly or using AC-coupling. When using the LVDS output type, set ch1_1p8vdet, ch2_1p8vdet, ch3_1p8vdet, and ch4_1p8vdet to match the VDDO12 and VDDO34.
- CML and LVPECL are only supported in an AC-coupled configuration. The receiver and the termination may only be connected through AC-coupling capacitors to the device pins.

LVCMOS outputs are designed for capacitive loads only. A series resistance should be used to adapt the
driver impedance to the trace impedance. For a typical 50-Ω trace, a resistor between 22 Ω to 33 Ω should be
used. The polarity of the positive and negative pins can be adjusted separately.

The output buffers support a wide frequency range of up to 350 MHz. Higher output frequencies up to 700 MHz are functional, but are not covered by electrical specifications.

8.3.3.1 Output Channel

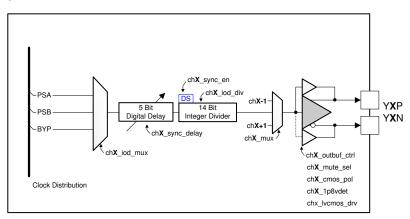


Figure 8-4. Clock Distribution Pre-Scaler Dividers

Figure 8-5. Clock Distribution, Output Channel

INSTANCES (1)	DIVISION VALUES			
PSA	4, 5, 6			
PSB	4, 5, 6			

(1) A known phase relationship for divider synchronization with mixed division values is ensured by architecture.

Table 8-3. Output Buffer Signal Standards

			•		
OUTPUT	LVCMOS	HCSL ⁽²⁾	LVDS	AC-CML ⁽¹⁾	AC-LVPECL ⁽¹⁾
Y0	X				
Y1		X	X	X	X
Y2	Х	X	X	X	X
Y3	X	X	X	X	X
Y4		x	X	х	X

⁽¹⁾ The common mode shall be provided externally through an external bias source, like a voltage divider or pullup resistor. The output buffer will provide sufficient swing.

Table 8-4. Output Channel Signal Selection

NO.	INPUT SOURCE	Y1 (N=1)	Y2 (N=2)	Y3 (N=3)	Y4 (N=4)
0	Channel N-1		x	x	x
1	IOD N	x	x	х	х
2	Channel N+1	х	х	х	

Table 8-5. Integer Divider Input Selection

NO.	SOURCE
0	Pre-scaler A
1	Pre-scaler B
3	Bypass

⁽²⁾ For highest performance it is recommended to use HCSL on output Y1 or Y4.



8.3.3.2 Divider Glitch-Less Update

The bit fields ch1_glitchless_en can be used to enable glitch-less output divider update. This feature ensures that the high pulse of a clock period is not cut off by the output divider update process. It ensures that setup and hold time of a receiver is not violated. The low pulse in the *transition* from earlier period to the new period is extended accordingly.

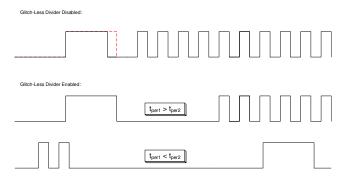


Figure 8-6. Glitch-Less Divider Update

8.3.4 Control Pins

The ultra-low power clock generator is controlled by multiple LVCMOS input pins.

EEPROMSEL acts as EEPROM page select. The CDCl6214 clock generator contains two pages of configuration settings. The level of this pin is sampled after device power-up. A low level selects page zero. A high level selects page one. The EEPROMSEL pin is a tri-level input pin. This third voltage level is automatically applied by an internal voltage divider. The mid-level is used to select an internal default where the serial interface is enabled.

RESETN/SYNC (pin 8), SCL (pin 12), and SDA (pin 19) have a secondary functionality and can act as general-purpose inputs and outputs (GPIO). This means that either the serial interface or the GPIO functionality can be active.

RESETN/SYNC resets the internal circuitry and is used in the initial power-up sequence. The pin can be reconfigured to act as synchronization input. The differential outputs are kept in mute while SYNC is low. When SYNC is high, outputs are active. Moreover status signals can be driven by this pin.

SCL can act as general-purpose input.

SDA can act as general-purpose input and output.

REFSEL is used to select between the input references to the PLL. A low level selects the crystal reference on XIN. A high level selects the differential input reference on REFP, REFN.

PIN			RECONFIGU	INF	TUT	OUTPUT	TERMIN	NATION
NO.	NAME	GPIO	RABLE?	2-LOGIC- LEVELS	3-LOGIC- LEVELS	2-LEVEL	PULLDOWN	PULLUP
23	EEPROMSEL	-	_	-	yes	_	50 kΩ	50 kΩ
20	STATUS	GPIO1	yes	yes	_	yes	_	50 kΩ
19	SDA	GPIO2	yes	yes	_	yes	-	_
12	SCL	GPIO3	yes	yes	_	_	_	_
11	OE	GPIO4	yes	yes	_	yes	_	50 kΩ
8	RESETN	GPIO0	yes	yes	_	yes	-	50 kΩ
4	REFSEL	-	_	_	yes	_	50 kΩ	50 kΩ

Table 8-6 Control and GPIO List

Table 8-7. GPIO - Input Signal List

SIGNAL NO. (1)	ABBREVIATION	DESCRIPTION
0	FREQ_INC	Frequency increment; increments the IOD ⁽²⁾
1	FREQ_DEC	Frequency decrement; decrements the IOD.(2)
2	OE (global)	Enables or disables all differential outputs Y[4:1] (bypass not affected). (3)
4	OE_Y1	Enables or disables Y1. (3)
5	OE_Y2	Enables or disables Y2. (3)
6	OE_Y3	Enables or disables Y3. (3)
7	OE_Y4	Enables or disables Y4. (3)

- (1) Signals from this list are available on pin 11 (OE / GPIO4) and pin 20 (STATUS / GPIO1), see GENERIC1.
- (2) Selected using bit mask in GENERIC3.
- (3) Disable / Mute behaviour configured individually using ch_mute_sel bit in GENERIC0 table.

Table 8-8. GPIO - Output Signal List

SIGNAL NO.(1)	ABBREVIATION	DESCRIPTION
0	PLL_LOCK	0 = PLL out of lock; 1 = indicates PLL in lock
1	XTAL_OSC	0 = crystal failure; 1 = crystal oscillates
2	CAL_DONE	0 = PLL (VCO) calibration ongoing; 1 = calibration done
3	CONF_DONE	0 = device logic busy; 1 = device operational
4	SYNC_DONE	0 = output sync ongoing, muted; 1 = outputs released operational
5	EEPROM_BUSY	0 = EEPROM idle; 1 = EEPROM access ongoing
6	EEPROM_Y12	0 = EEPROM pin sees low level; 1 = EEPROM pin sees high level
7	EEPROM_M12	0 = EEPROM pin sees low or high level; 1 = EEPROM pin sees mid level
8	I2C_LSB	Indicates I ² C target address LSB config from loaded EEPROM
9	CLK_FSM	Clock, State machine
10	CLK_PFD_REF	Clock, PFD, reference
11	CLK_PFD_FB	Clock, PFD, feedback
12	BUF_SYNC	buffered SYNC pin
13	BUF_SCL	buffered SCL pin
14	BUF_SDA	buffered received SDA pin

⁽¹⁾ Signals from this list are available on pin 8 (RESETN/SYNC or GPIO0), pin 11 (OE / GPIO4) and pin 20 (STATUS / GPIO1).

8.3.4.1 Global and Individual Output Enable: OE and OE_Y[4:1]

The output enable functionality allows to enable or disable all or a specific output buffer. The bypass copy on Y0 is excluded from the global output enable signal. When an output is disabled, it drives a configurable mute-state, ch[4:1]_mute-sel. When the serial interface is deactivated one can use all individual output enable signals at the same time, see mode. The individual output enable signal controls the respective output channel integer divider to gate the clock. Therefore each integer divider needs to be active. When multiple outputs are sourced from the same integer divider, the respective OE signal will enable/disable the output(s). ¹

Note

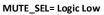
When multiple output enable signals are configured on multiple-GPIO pins, then the global output enable OE has higher priority than the individual output enable OE[4:1]. An individual output enable OE[4:1] may only be configured on a single pin.

¹ The GPIO direction of pins 12 and 19 is automatically set through the mode bit. Pin 11 and 20 must be set as inputs using gpio1_dir_sel and gpio4_dir_sel bit in the Table 10-3 table.



The individual output enable signal enables and disables the respective output in a deterministic way. Therefore the high and low level of the signal is qualified by counting four cycles of the respective output clock. The following steps can be seen in Figure 8-7:

- 1. The OE falling edge which disables the outputs.
- 2. Transition from logic high to logic low / logic low to logic high for Y2 after four rising edges.
- 3. Transition from logic high to logic low / logic low to logic high for Y1 after four rising edges.
- 4. The OE rising edge which enables the outputs.
- 5. Output Y2 starts toggling after four rising edges.
- 6. Output Y1 starts toggling after four rising edges.



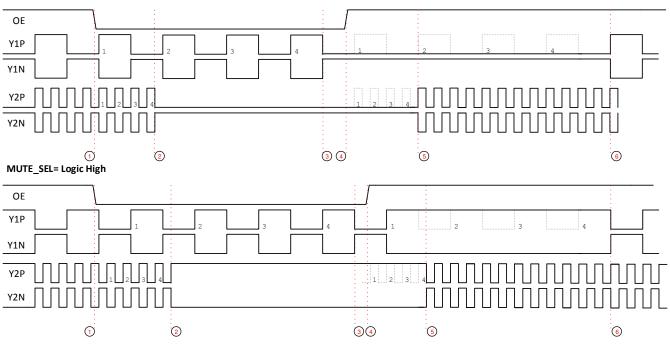


Figure 8-7. Individual Output Enable and Disable

Note

The deterministic behaviour of the individual output enable is designed for an output frequency up to 200 MHz.

8.3.5 Operation Modes

The device can operate in different modes.

Following operating modes can be set and the GPIOs configured. An operating mode change only becomes effective when it is loaded from the EEPROM after a power cycle.

Table 8-9. Modes of Operation

DESCRIPTION	MODE	REFSEL	EEPROMSEL	GPIO4	GPIO3	GPIO2	GPIO1
I ² C + GPIOs	Fallback	М	М	I/O	SCL	SDA	I/O
I ² C + GPIOs	0	LH	LH	I/O	SCL	SDA	I/O
OEs	1	LH	LH	OE4	OE3	OE2	OE1

8.3.6 Divider Synchronization - SYNC

The output dividers can be reset in a deterministic way. This can be achieved using the sync bit or the pin 8 configured for SYNC function using <code>gpio0_input_sel</code> and <code>gpio0_dir_sel</code>. The level of the pin is qualified internally using the reference frequency at the PFD. A low level will mute the outputs. A high level will synchronously release all output dividers to operation, so that all outputs share a common rising edge, see Figure 8-8. The first rising edge can be individually delayed in steps of the respective pre-scaler period, up to 32 cycles using <code>ch1_sync_delay</code>. This allows to compensate external delays like routing mismatch, cables or inherent delays introduced by logic gates in an FPGA design. Each channel can be included or excluded from the SYNC process using <code>ch1_sync_en</code>. ^{2 3}

For a deterministic behaviour over power-cycles seen from input to output the reference divider must be set to 1. It should not divide the reference clock nor should the reference doubler be used.

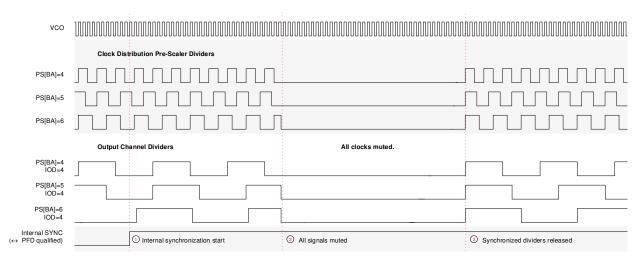


Figure 8-8. Divider Synchronization

PRE-SCALER STEP IN ns **VCO FREQUENCY IN MHz** /4 /5 /6 2400 1.67 2.08 2.50 2457.6 1.63 2.03 2.44 2500 1.60 2.00 2.40 2800 1.43 1.79 2.14

Table 8-10. Digital Delay Step Size

8.3.7 EEPROM - Cyclic Redundancy Check

The device contains a cyclic redundancy check (CRC) function for reads from the EEPROM to the device registers. At start-up the EEPROM will be read internally and a CRC value calculated. One of the EEPROM words contains an earlier stored CRC value. The stored and the actual CRC value are compared and the result transferred to STATUS1 register. The CRC calculation can be triggered again by writing a '1' to the update_crc bit. A mismatch between stored and calculated CRC value is informational only and non-blocking to the device operation. Just reading back the CRC status bit and the live CRC value can speed up in-system EEPROM programming and avoid reading back each word of the EEPROM for known configurations.

The polynomial used is CCITT-CRC16: $x^{16} + x^{12} + x^5 + 1$.

² ch[4:1]_sync_en may only be activated with an active clock source selected in ch1_iod_mux bit in the Table 10-31 table.

The LVCMOS bypass output Y0 is not part of the SYNC process, neither are the dividers of the PLL.



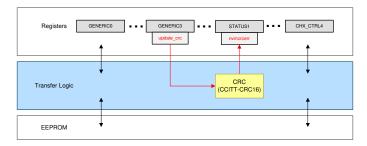


Figure 8-9. EEPROM CRC

8.3.8 Power Supplies

The CDCI6214 provides multiple power supply pins. Each of the power supplies supports 1.8 V, 2.5 V, or 3.3 V. Internal low-dropout regulators (LDO) source the internal blocks and allow each pin to be supplied with its individual supply voltage. The VDDREF pin supplies the control pins and the serial interface. Therefore, any pullup resistors shall be connected to the same domain as VDDREF. By default the LDOs are configured for 1.8-V ±5% operation.

8.3.8.1 Power Management

The device is very flexible with respect to internal power management. Each block offers a power-down bit and can be disabled to save power when the block is not required. The available bits are illustrated in Figure 8-10. The bypass output Y0 is connected to the pdn_ch4 bit. Each output channel has a bit which should be adapted to the applied supply voltage, ch[4:1]_1p8vdet.

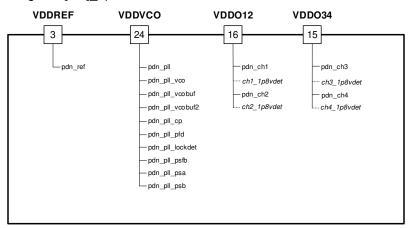


Figure 8-10. Power Management

8.4 Device Functional Modes

8.4.1 Pin Mode

In pin mode, pins 12 and 19 are input pins that act as individual output enable pins. Together with pins 11 and 20, this mode allows for one output enable pin per output channel.

8.4.2 Serial Interface Mode

In serial interface mode, pins 12 and 19 are configured as an I²C interface.

8.4.2.1 Fall-Back Mode

As the programming interface can be intentionally deactivated using the EEPROM, an accidental disabling of the I²C blocks further access to the device. The serial interface can be forced using the fall-back mode. To enter this mode, the user leaves pin 4 and pin 23 floating while the supply voltage is applied to VDDREF. In this mode, pin 11 is preconfigured as an input and pin 20 is configured as an output.

8.5 Programming

The CDCl6214 ultra-low power clock generator provides an I^2C -compatible serial interface for register and EEPROM access. The device is compatible to standard-mode I^2C at 100 kHz and the fast-mode I^2C at 400-kHz clock frequency.

Table 8-11. I²C-Compatible Serial Interface, Target Address Byte

7	6	5	4	3	2	1	0
	Target Address A[6:0] ⁽¹⁾						

- (1) The target address consists of two sections. The hardwired MSBs A[6:2] and the software-selectable LSBs A[1:0].
- (2) The R/W# bit indicates a read (1) or a write (0) transfer.

Table 8-12 shows the target address decoding with respect to EEPROMSEL pin. This enables the user to avoid in-system conflicts with different configurations, as the selected EEPROM page can be reflected in the target address least significant bit A0. Moreover a device being powered up in the silicon default, can always be expected under the default address of 0xE9 for reads (or 0xE8 for writes).

Table 8-12. I²C-Compatible Serial Interface, Programmable Target Address

A6	A5	A4	A3	A2	A1	A0	EEPROMSEL	DESCRIPTION
					0	0	MID	Device Default
1	1	1	0	1	1	I2C_A0 ⁽¹⁾	LOW	EEPROM, Page 0
					1	I2C_A0 ⁽²⁾	HIGH	EEPROM, Page 1

- (1) Configuration Bit in EEPROM Page 0, default value of 0.
- (2) Configuration Bit in EEPROM Page 1, default value of 1.

The serial interface uses the following protocol as shown in Figure 8-11. The target address is followed by a word-wide register offset and a word-wide register value.

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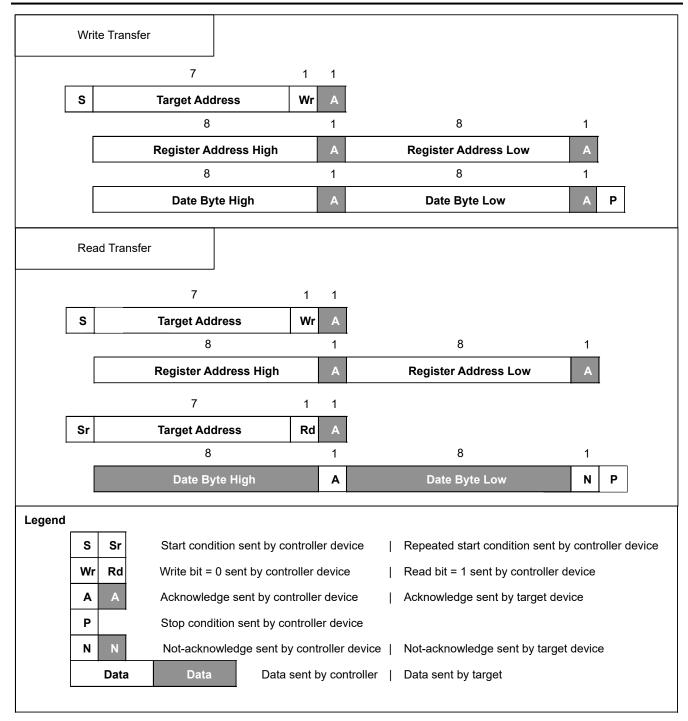


Figure 8-11. I²C-Compatible Serial Interface, Supported Protocol

8.5.1 Recommended Programming Procedure

TI recommends programming the registers of the device in the following way:

- 1. Ensure that ee lock is set when overwriting the EEPROM.
- 2. Configure the voltage domain bits appropriately ch[4:1]_1p8vdetch[4:1]_1p8vdet.
- 3. Program register addresses in descending order from 0x44 to 0x00 including all register addresses with reserved values.

8.5.2 EEPROM Access

Note

The EEPROM word write access time is typically 8 ms. The EEPROM_BUSY signal indicates when the EEPROM is busy and can be observed as a status signal on a GPIO pin to optimally time the writes (for example, in gpio4_output_sel).

There are two methods to write into the internal EEPROM:

- 1. Register Commit
- 2. EEPROM Direct Access

Use the following steps to bring the device into a known state and be able to conduct the programming:

- 1. Power down all device supplies
- 2. Apply RESETN=LOW.
- 3. Apply REFSEL=MID (leave tri-stated).
- 4. Apply EEPROMSEL=MID (leave tri-stated).
- 5. Apply 1.8 V/2.5 V/3.3 V to all device supplies. When device operation is not required, only apply 1.8 V/2.5V/3.3 V to VDDREF.
- 6. Apply RESETN=HIGH.
- 7. Use the I²C interface to configure the device using target address 0x74. See Table 8-12 for more details.

In the *Register Commit* flow all bits from the device registers are copied into the EEPROM. The recommended flow is:

- 1. Pre-configure the device as desired, except the serial interface using mode.
- 2. Write 1 to recal to calibrate the VCO in this operation mode.
- 3. Select the EEPROM page, to copy the register settings into, using regcommit_page.
- 4. Unlock the EEPROM for write access with ee lock = 0x5
- 5. Start the commit operation by writing a 1 to regcommit
- 6. Force a CRC update by writing a 1 to update_crc.
- 7. Read back the calculated CRC in nymlcrc.
- 8. Store the read CRC value in the EEPROM by writing 0x3F to nvm_wr_addr and then the CRC value to nvm_wr_data.

In the *EEPROM Direct Access* flow the EEPROM words are directly accessed using the address and the data bit-fields. The recommended flow is:

- 1. Prepare an EEPROM image consisting of 64 words.
- 2. Unlock the EEPROM for write access with ee lock = 0x5
- 3. Write the initial address offset to the address bit-field. Write a 0x00 to nvm wr addr.
- 4. Loop through the EEPROM image from address 0 to 63 by writing each word from the image to nvm_wr_data. The EEPROM word address is automatically incremented by every write access to nvm_wr_data.
- The EEPROM read is similar to EEPROM write. First write 0x00 to nvm_rd_addr, then loop through all bytes
 by reading from nvm_rd_data. The EEPROM word address is automatically incremented by every write
 access to nvm_rd_data.

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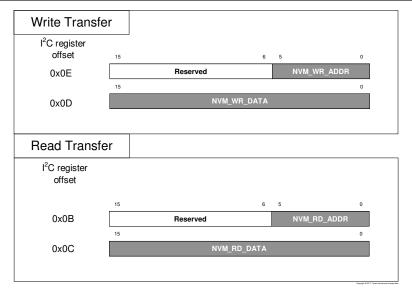


Figure 8-12. EEPROM Direct Access Using I²C



8.5.3 Device Defaults

The CDCI6214 contains the following defaults:

Table 8-13. CDCI6214 Register Defaults

ADDRESS	DEFAULT	EEPROM PAGE 0	EEPROM PAGE 1
0x46	0x00460000	0x00460000	0x00460000
0x45	0x00450000	0x00450000	0x00450000
0x44	0x00440000	0x00440000	0x00440000
0x43	0x00430020	0x00430020	0x00430020
0x42	0x00420000	0x00420200	0x00420200
0x41	0x00410F34	0x00410F34	0x00410F34
0x40	0x0040000D	0x0040000D	0x0040000D
0x3F	0x003F0210	0x003F4210	0x003F4210
0x3E	0x003E4210	0x003E4218	0x003E4218
0x3D	0x003D1000	0x003D1500	0x003D1500
0x3C	0x003C0010	0x003C0018	0x003C0018
0x3B	0x003B0009	0x003B0061	0x003B0061
0x3A	0x003A0008	0x003A0008	0x003A0008
0x39	0x00390A65	0x00398851	0x00398851
0x38	0x00380405	0x00380409	0x00380008
0x37	0x00370004	0x00370006	0x00370000
0x36	0x00360000	0x00360000	0x00360000
0x35	0x00358000	0x00358000	0x00358000
0x34	0x00340008	0x00340008	0x00340008
0x33	0x00330A65	0x00338861	0x00338861
0x32	0x00320405	0x00320429	0x00320431
0x31	0x00310004	0x00310006	0x00310006
0x30	0x00300000	0x00300000	0x00300000
0x2F	0x002F8000	0x002F8000	0x002F8000
0x2E	0x002E0008	0x002E0008	0x002E0008
0x2D	0x002D0A65	0x002D0851	0x002D0851
0x2C	0x002C0405	0x002C0409	0x002C0010
0x2B	0x002B0004	0x002B0006	0x002B0000
0x2A	0x002A0000	0x002A0000	0x002A0000
0x29	0x00298000	0x00298000	0x00298000
0x28	0x00280008	0x00280008	0x00280008
0x27	0x00270A65	0x00270851	0x00270851
0x26	0x00260405	0x00260409	0x00260409
0x25	0x00250004	0x00250006	0x00250006
0x24	0x00240000	0x00240000	0x00240000
0x23	0x00238000	0x00238000	0x00238000
0x22	0x00220050	0x00220050	0x00220050
0x21	0x00210007	0x00210007	0x00210007
0x20	0x00200000	0x00200000	0x00200000
0x1F	0x001F1E72	0x001F1E72	0x001F1E72
0x1E	0x001E5140	0x001E5140	0x001E5140
0x1D	0x001D400A	0x001D000C	0x001D000C
0x1C	0x001C0000	0x001C0000	0x001C0000
0x1B	0x001B0000	0x001B0000	0x001B0000
0x1A	0x001A0718	0x001A0A1C	0x001A0A1C
0x19	0x00190000	0x00190406	0x00192406

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Table 8-13. CDCI6214 Register Defaults (continued)

ADDRESS	DEFAULT	EEPROM PAGE 0	EEPROM PAGE 1
0x18	0x00180601	0x00180601	0x00180601
0x17	0x00170000	0x00170595	0x00170595
0x16	0x00160000	0x00160000	0x00160000
0x15	0x00150000	0x00150000	0x00150000
0x14	0x00140000	0x00140001	0x00140001
0x13	0x00130000	0x00130000	0x00130000
0x12	0x00120000	0x0012FFFF	0x0012FFFF
0x11	0x001126C4	0x001126C4	0x001126C4
0x10	0x0010921F	0x0010921F	0x0010921F
0xF	0x000FA037	0x000FA037	0x000FA037
0xE	0x000E0000	0x000E0000	0x000E0000
0xD	0x000D0000	0x000D0000	0x000D0000
0xC	0x000C0000	0x000C0000	0x000C0000
0xB	0x000B0000	0x000B0000	0x000B0000
0xA	0x000A0000	0x000AC964	0x000AC964
0x9	0x00090000	0x0009C964	0x0009C964
0x8	0x00080000	0x00080001	0x00080001
0x7	0x00070000	0x00070C0D	0x00070C0D
0x6	0x00060000	0x0006159F	0x000619CA
0x5	0x00050028	0x00050028	0x00050028
0x4	0x00040055	0x00040055	0x000400DD
0x3	0x00030000	0x00030000	0x00030800
0x2	0x00020053	0x00020053	0x00020053
0x1	0x00016882	0x00016865	0x00016864
0x0	0x00000000	0x00000001	0x00000000

Table 8-14. Default EEPROM Image

ADDRESS	Section	Word Value
0x0	Base	0xEE00
0x1		0x490F
0x2		0x0362
0x3		0x0E00
0x4		0x1400
0x5		0xC104
0x6		0x0C00
0x7		0x5000
0x8		0x0861
0x9		0x8421
0xA		0x0006
0xB		0x0000

Table 8-14. Default EEPROM Image (continued)

ADDRESS	Section	Word Value
0xC		0x6501
0xD		0x5368
0xE		0xAA80
0xF		0x4382
0x10		0x0001
0x11		0x0030
0x12		0x4500
0x13		0x79C9
0x14		0x8000
0x15		0x0C00
0x16		0x1200
0x17		0x2904
0x18	D 0	0x0002
0x19	Page 0	0x3002
0x1A		0x4800
0x1B		0xA410
0x1C		8000x0
0x1D		0xC008
0x1E		0x2000
0x1F		0x1045
0x20		0x0033
0x21		0x0020
0x22		0x8003
0x23		0x4104
0x24		0x39CA
0x25		0x0000



Table 8-14. Default EEPROM Image (continued)

ADDRESS	Section	Word Value
0x26	Section	0x6400
	_	
0x27		0x5368
0x28		0xEE80
0x29		0x4382
0x2A		0x0001
0x2B		0x0030
0x2C		0x4500
0x2D		0x79C9
0x2E		0x8000
0x2F		0x0C00
0x30		0x1200
0x31		0x2904
0x32		0x0002
0x33	Page 1	0x0002
0x34		0x8000
0x35	1	0xA400
0x36	1	0x0008
0x37		0xC008
0x38		0x2000
0x39		0x1046
0x3A		0x0033
0x3B		0x0020
0x3C		0x0000
0x3D		0x4004
0x3E		0x39CA
0x3F		0xC964



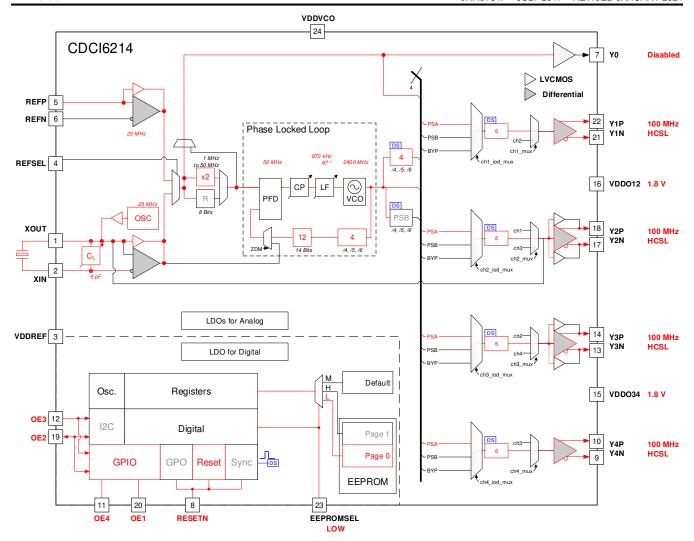


Figure 8-13. CDCI6214 - Pre-Configured EEPROM Page 0



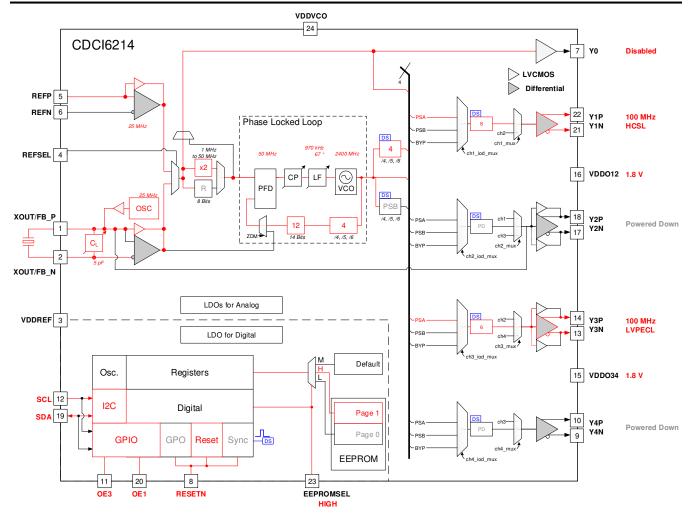


Figure 8-14. CDCI6214 - Pre-Configured EEPROM Page 1

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9 Application and Implementation

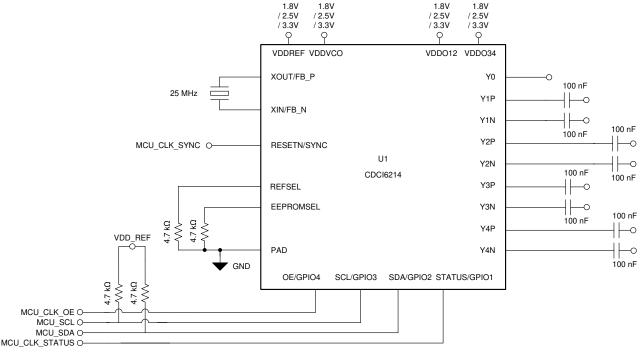
Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

An ultra-low power clock generator is designed to drive clocks in industrial, portable and data center applications. The device is flexible in its configuration and be pre-preprogramed with two separate configuration. For example a production test and an application configuration, or two different configurations for two flavors of a product. The internal EEPROM is protected by a CRC hash which is available as a status bit. The two EEPROM pages are selected using a control pin. As each major block of the device is powered by its own supply pin, the device can easily be used for signal translation and to accommodate various supply voltages which may be available in a system. Up to five different frequencies can be generated from a single device and feed different parts of an application. Each of the four differential outputs supports various signal standards. The general purpose pin functionality can provide status information to other parts of the system and can add modularity and flexibility to an application. Clock outputs can be muted individually or globally, the division ratio updated, the output dividers synchronized and a spread spectrum function enabled or disabled. The clock generator PLL can also be used in a zero delay mode which will compensate most of the seen phase delay between an external reference clock and the output clocks. Together with an external feedback option this allows to compensate traces on top of the digital delay steps provided inside the device. All these features make the ultra-low power clock generator for design library integration and re-use in modular projects.

9.2 Typical Applications



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Figure 9-1. Typical Serial Interface Application Schematic

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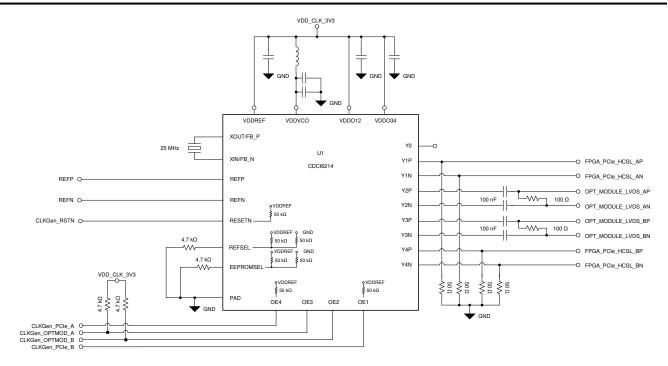


Figure 9-2. Typical Individual Output Enable Application Schematic

9.2.1 Design Requirements

For this example, the design parameters are listed in Table 9-1

 $\begin{array}{c|c} \textbf{PARAMETER} & \textbf{EXAMPLE VALUE} \\ \hline t_{VDD} & \text{Larger than 50 } \mu \text{s and smaller than 3 ms} \\ \hline t_{PWL_SYNC} & \text{Larger than (1 / } f_{XIN}) \\ \hline f_{XIN} & \text{Crystal 8 MHz to 50 MHz} \\ \hline dV_{IN} / dT & \text{Input slew rate for external clock reference better than 3 V / ns} \\ \hline \end{array}$

Table 9-1. Design Parameters

9.2.2 Detailed Design Procedure

For this application, TI recommends the following steps:

- 1. Decide how the device shall receive the register settings to plan for in-system programming of the EEPROM.
- 2. Choose which operation mode to use on the device (I²C or GPIOs) and which pins are inputs and which are outputs (see registers

GENERICO

GENERIC1

, and

GENERIC2

).

- 3. Consider that the serial interface and the GPIOs are supplied by VDDREF as well as the input pins (for example, a 3.3-V crystal oscillator (XO) driving XIN forces uses 3.3-V I²C).
- 4. Keep track of which voltage levels the output supplies will have. There are configuration bits in the output channels (see CH1_CTRL5,

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CH2_CTRL5

- , CH3_CTRL5, and CH4_CTRL5).
- 5. Consider which output frequency has the most stringent phase noise specifications. Select this frequency to decide on the reference and VCO frequency.
- 6. Cross-check if your specific bandwidth requirement for an external reference can be achieved using the internal loop filter components (see registers PLL1 and PLL2).
- 7. Optimize the clock distribution using output muxes to run the least amount of blocks to conserve power,

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8. For HCSL output buffer format, optimize the signal integrity and slew rate at the receiver input using a series resistor between device pin and the 50 Ω termination to GND.Y1,Y4 provide higher slew rates compared to Y2,Y3.

Use Equation 1 through Equation 4 to calculate the a basic frequency plan or use the provided software TICS Pro to generate settings.

Note

The user has to ensure PLL stability is given by applying the adequate loop filter and charge pump settings. A phase margin of $\geq 68^{\circ}$ is recommended. The target bandwidth is recommended between 600 kHz .. 1100 kHz.

$$f_{Y0} = f_{XIN} = f_{REF} \tag{1}$$

$$f_{PFD} = f_{REF} / ip_ref_div$$
 (2)

where

- ip ref div ≥ 1
- 1 MHz <= f_{PFD} <= 100 MHz

$$f_{VCO} = f_{PFD} \cdot pll_nc \cdot (pll_ps + 4)$$
(3)

with

- 2400 <= f_{VCO} <= 2800
- 0 <= pll ps <= 2

$$f_{Y[4:1]} = f_{VCO} / ((pll_ps[ab] + 4) \cdot ch[4:1]_iod_div)$$
 (4)

with

- 0 <= pll_ps[ab] <= 2
- 1 <= ch[4:1] iod div <= 16383
- 44.1 kHz <= f_{Y[4:1]} <= 350 MHz

with

- 1 <= IP REF DIV <= 255
- IP_EN_DBLR = 0
- 1 MHz <= f_{PFD} <= 100 MHz

with

- IP REF DIV = 0
- IP_EN_DBLR = 1
- 1 MHz <= f_{PFD} <= 100 MHz

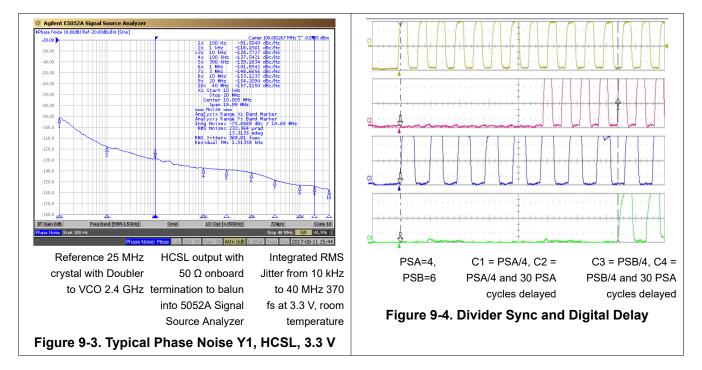
with

- 2400 <= f_{VCO} <= 2800
- 0 <= PLL_PS_MODE <= 2

with

- 0 <= PLL PS[AB] MODE <= 2
- 1 <= CH[4:1] IOD DIV <= 16383
- 44.1 kHz \leq f_{Y[4:1]} \leq 350 MHz

9.2.3 Application Curves



9.3 Do's and Don'ts

The maximum swing and level must match to the applied VDDREF (for example, for a 3.3-V XO as reference, VDDREF must be 3.3 V).

VDDREF and VDDVCO must be powered from the same supply voltage.

9.4 Initialization Setup

The device digital logic starts after the internal power-on-release circuit triggered (POR). The digital core is connected to the VDDREF domain. The EEPROM settings are loaded into the device registers and the new settings applied to the device. The EEPROM page is selected according to the EEPROMSEL pin logic level. A low level loads *page 0*, and a logic high level loads *page 1*. By default, the differential outputs are muted for the initial VCO calibration and PLL lock process. After the PLL circuit achieved a phase lock to the input reference, the output dividers are synchronized and then released to operation. By default, pin 8 is configured as RESETN pin (see gpio0_dir_sel and gpio0_input_sel). The start of the initialization sequence, as well the as serial interface, can be kept in reset using RESETN= LOW. When pin 8 is not configured as RESETN, the device initialization relies on the POR triggered by application of VDDREF.



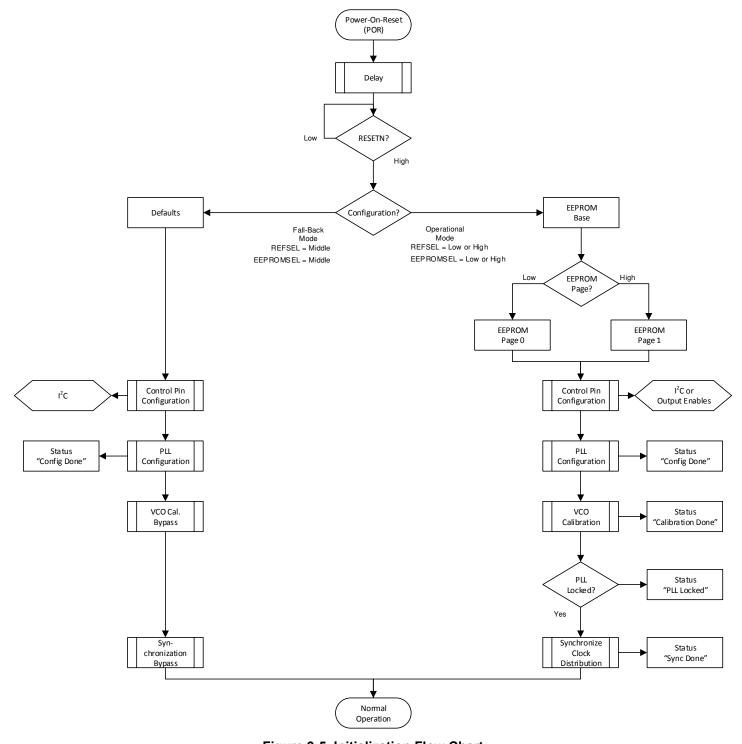


Figure 9-5. Initialization Flow Chart

The pins 8, 11, 12, 19, and 20 are general-purpose inputs and outputs (GPIO). The functions are determined through the register settings saved in the selected EEPROM page. See Generic0, Generic1, and Ceneric2for the relevant bit-fields.

The EEPROM allows to choose between two modes of operation: pin Mode and serial interface mode. This is done using mode.

9.5 Power Supply Recommendations

9.5.1 Power-Up Sequence

There are no restrictions from the device for applying power to the supply pins. From an application perspective, TI recommends to either apply all VDDs at the same time or apply VDDREF first. The digital core is connected to VDDREF, and thus the settings of the EEPROM are applied automatically. All VDDs should reach 95% of final value within 2 ms. RESETN should be held low before VDDREF reaches 95% of the final value.

TI recommends adding a $4.7-k\Omega$ pullup resistor on RESETN and a 470-nF capacitor to ground to provide additional delay in release of RESETN at power-up. When powering up the CDCI6214 from reset, the rise of the RESETN pin must be delayed to allow the voltage on the VDD pins to stabilize.

An unstable voltage on the VDD pin may cause an improper device startup with the rise of the RESETN pin, resulting in a PLL unlock. VDD instability may occur in cases where VDD is toggled repeatedly and does not ramp with appropriate settling time. The power supply must ramp and be stable within the time specified in the *Timing Characteristics* table. In the event of a PLL unlock at startup, recalibrate the PLL. Either setting the recal bit, R0[4], to a '1' or pulling the RESETN pin low then high will recalibrate the PLL.

9.5.2 De-Coupling

TI recommends isolating all power supplies using a ferrite bead and provide decoupling for each of the supplies. TI also recommends optimizing the decoupling for the respective layout and consider the power supply impedance and optimize for the individual frequency plan.

An example for a decoupling per supply pin: 1x 4.7 µF, 1x 470 nF, and 1x 100 nF.

9.6 Layout

9.6.1 Layout Guidelines

For this example, follow these guidelines:

- Isolate inputs and outputs using a GND shield. Figure 9-6 routes all inputs and outputs as differential pairs.
- Isolate outputs to adjacent outputs when generating multiple frequencies.
- Isolate the crystal area, connect the GND pads of the crystal package and flood the adjacent area. Figure 9-7 shows a foot print which supports multiple crystal sizes.
- Try to avoid impedance jumps in the fan-in and fan-out areas when possible.
- Use five VIAs to connect the thermal pad to a solid GND plane. Full-through VIAs are preferred.
- Place decoupling capacitors with small capacitance values very close to the supply pins. Try to place them
 very close on the same layer or directly on the backside layer. Larger values can be placed more far away.
 Figure 9-7 shows three de-coupling capacitors close to the device. Ferrite beads are recommended to isolate
 the different frequency domains and the VDDVCO domain.
- Preferably use multiple VIAs to connect wide supply traces to the respective power planes.



9.6.2 Layout Examples

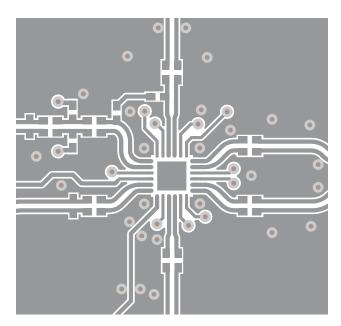


Figure 9-6. Layout Example, Top Layer

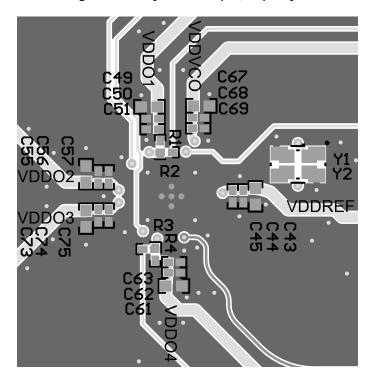


Figure 9-7. Layout Example, Bottom Layer

Land Pattern Example

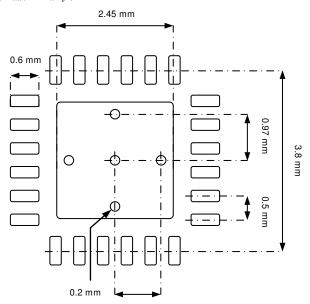


Figure 9-8. Layout Example, Land Pattern



10 Register Maps 10.1 CDCI6214 Registers

Table 10-1 lists the memory-mapped registers for the CDCI6214.

Note

All register offset addresses not listed in Table 10-1 should be considered as reserved locations and the register contents should not be modified.

Note

All bit-field combinations not listed in the description column should be considered as reserved combinations and should only be programmed using the given values.

Table 10-1. CDCI6214 Registers

ADDRESS	DDRESS ACRONYM REGISTER NAME		SECTION
0h	GENERIC0	Generic setting, device operation mode, synchronization, control pins, reset, and power down.	Go
1h	GENERIC1	Generic settings, GPIO input signal selection.	Go
2h	GENERIC2	Generic settings, GPIO output signal selection.	Go
3h	GENERIC3	Generic settings, EEPROM and frequency increment / decrement.	Go
4h	POWER0	Power-down bits, output channels.	Go
5h	POWER1	Power-down bits, phase-locked-loop.	Go
6h	STATUS0	Status information, calibration bus.	Go
7h	STATUS1	Status information, PLL lock and EEPROM.	Go
8h	STATUS2	Status information, miscellaneous	Go
9h	STATUS3	Status information, live CRC of EEPROM	Go
Ah	EEPROM0	EEPROM, stored CRC of EEPROM	Go
Bh	EEPROM1	EEPROM, direct access read address	Go
Ch	EEPROM2	EEPROM, direct access read data	Go
Dh	EEPROM3	EEPROM, direct access write address	Go
Eh	EEPROM4	EEPROM, direct access write data	Go
Fh	STARTUP0	Start-up configuration, EEPROM lock, auto-calibration, and I2C glitch filter	Go
10h	STARTUP1	Start-up configuration, digital state machine counters	Go
11h	STARTUP2	Start-up configuration, digital state machine counters	Go
18h	REV0	Revision ID	Go
1Ah	INPUT0	Input reference, buffer configuration, and crystal oscillator controls.	Go
1Bh	INPUT1	Input reference, reference divider, and bypass buffers.	Go
1Ch	INPUT_DBG0	Input reference debug, status pin buffers.	Go
1Dh	PLL0	PLL, feedback dividers.	Go
1Eh	PLL1	PLL, charge pump current and clock distribution pre-scaler dividers.	Go
1Fh	PLL2	PLL, loop filter configuration	Go
21h	PLL4	PLL, lock detector and PFD delay	Go
23h	CH1_CTRL0	Output channel 1, RESERVED	Go
24h	CH1_CTRL1	Output channel 1, RESERVED	Go
25h	CH1_CTRL2	Output channel 1, integer divider and mux control.	Go
26h	CH1_CTRL3	Output channel 1, synchronization, digital delay, output buffer, mux and mute controls.	Go
27h	CH1_CTRL4	Output channel 1, divider glitchless enable and spread spectrum controls.	Go

Table 10-1. CDCI6214 Registers (continued)

ADDRESS	ACRONYM	REGISTER NAME	SECTION
28h	CH1_CTRL5	Output channel 1, RESERVED	Go
29h	CH2_CTRL0	Output channel 2, RESERVED	Go
2Ah	CH2_CTRL1	Output channel 2, RESERVED	Go
2Bh	CH2_CTRL2	Output channel 2, integer divider and mux control.	Go
2Ch	CH2_CTRL3	Output channel 2, synchronization, digital delay, output buffer, mux and mute controls.	Go
2Dh	CH2_CTRL4	Output channel 2, divider glitchless enable and spread spectrum controls.	Go
2Eh	CH2_CTRL5	Output channel 2 , RESERVED	Go
2Fh	CH3_CTRL0	Output channel 3, RESERVED	Go
30h	CH3_CTRL1	Output channel 3, RESERVED	Go
31h	CH3_CTRL2	Output channel 3, integer divider and mux control.	Go
32h	CH3_CTRL3	Output channel 3, synchronization, digital delay, output buffer, mux and mute controls.	Go
33h	CH3_CTRL4	Output channel 3, divider glitchless enable and spread spectrum controls.	Go
34h	CH3_CTRL5	Output channel 3, RESERVED	Go
35h	CH4_CTRL0	Output channel 4, RESERVED	Go
36h	CH4_CTRL1	Output channel 4, RESERVED	Go
37h	CH4_CTRL2	Output channel 4, integer divider and mux control.	Go
38h	CH4_CTRL3	Output channel 4, synchronization, digital delay, output buffer, mux and mute controls.	Go
39h	CH4_CTRL4	Output channel 4, divider glitchless enable and spread spectrum controls.	Go
3Ah	CH4_CTRL5	Output channel 4, RESERVED	Go
3Bh	CHX_CTRL0	Output channels, generic clock distribution and bypass output controls.	Go
3Ch	CHX_CTRL1	Output channels, RESERVED	Go
3Dh	CHX_CTRL2	Output channels, RESERVED	Go
3Eh	CHX_CTRL3	Output channels, RESERVED	Go
3Fh	CHX_CTRL4	Output channels, RESERVED	Go

Complex bit access types are encoded to fit into small table cells. Table 10-2 shows the codes that are used for access types in this section.

Table 10-2. CDCI6214 Access Type Codes

ACCESS TYPE	CODE	DESCRIPTION						
READ TYPE	READ TYPE							
R	R	Read						
RC	C R	to Clear Read						
WRITE TYPE	WRITE TYPE							
W	W	Write						
WEX	W	Write						
WMC	W	Write						
WPD	W	Write						
WSC	w	Write						
WST	W	Write						
RESET OR DEF	RESET OR DEFAULT VALUE							
-n		Value after reset or the default value						

10.1.1 GENERICO Register (Address = 0h) [reset = 0h]

GENERIC0 is shown in Figure 10-1 and described in Table 10-3.

Return to Summary Table.

Figure 10-1. GENERICO Register

15	14	13	12	11	10	9	8
i2c_a0	gpio0_input_sel	gpio4_dir_sel	gpio1_dir_sel	gpio0_dir_sel	zdm_clocksel	RESERVED	zdm_mode
R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h
7	6	5	4	3	2	1	0
RESERVED	pll_rst_lockdet	sync	recal	resetn_soft	swrst	powerdown	mode
R/W-0h	R/W-0h	R/WSC-0h	R/WSC-0h	R/W-0h	R/WSC-0h	R/WPD-0h	R/W-0h

Table 10-3. GENERICO Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION			
15	i2c_a0	R/W	0h	When regcommit is used to program an EEPROM page, using regcommit_page, this defines the LSB of the I ² C target address. When a configuration is loaded into the registers from an EEPROM page, this represents the saved LSB bit.			
14	gpio0_input_sel	R/W	Oh	Input signal select for GPIO0, Pin 8. 0h = RESETN 1h = SYNC			
13	gpio4_dir_sel	R/W	Oh	GPIO4 direction select. 0h = Input 1h = Output			
12	gpio1_dir_sel	R/W	Oh	GPIO1 direction select. 0h = Input 1h = Output			
11	gpio0_dir_sel	R/W	Oh	Direction select for Pin 8. 0h = Input 1h = Output			
10	zdm_clocksel	R/W	0h	Selects the internal or external clock for calibration, in the ZDM mode. In non-ZDM mode, always internal clock will be selected and this register doesn't have any meaning. Oh = Internal Feedback 1h = External Feedback			
9	RESERVED	R/W	0h	RESERVED			
8	zdm_mode	R/W	Oh	Zero Delay Mode 0h = ZDM Off 1h = ZDM On			
7	RESERVED	R/W	0h	RESERVED.			
6	pll_rst_lockdet	R/W	0h	Reset (active high) to PLL lock detect circuit.			

Table 10-3. GENERICO Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION (CONTINUES)
5	sync	R/WSC	0h	Generates sync pulse (for output decoder). This is a self clearing register bit and writing '1' will create the SYNC pulse.
4	recal	R/WSC	0h	Self clearing bit. Writing '1' will do the re-calibration. For example - after the configuration followed by calibration if '1' is written to this register the calibration engine will start with the current capcode and cross code.
3	resetn_soft	R/W	Oh	Configure the pin RESETN/SYNC as a soft reset. 0h = Hard Reset (reset state machines and registers) 1h = Soft Reset (state machines only, register content stays as is)
2	swrst	R/WSC	0h	Soft reset bit. This is a self clearing bit. Writing a '0' has no effect and writing a '1' creates a reset pulse which resets the digital logic except the programmable registers. Also, this soft reset has similar effect on digital logic as hard reset (RESENTN/SYNC). Soft reset will restart the configuration and calibration.
1	powerdown	R/WPD	0h	Analog Power Down. 0h = Active 1h = Power down
0	mode	R/W	0h	Mode of Operation. 0h = Serial Interface, I2C 1h = Pin Mode, Output Enable

10.1.2 GENERIC1 Register (Address = 1h) [reset = 6A32h]

GENERIC1 is shown in Figure 10-2 and described in Table 10-4.

Return to Summary Table.

Figure 10-2. GENERIC1 Register

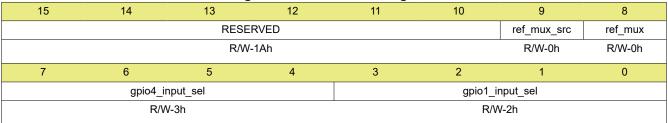


Table 10-4. GENERIC1 Register Field Descriptions

	Table 10-4. GENERIC1 Register Field Descriptions							
BIT	FIELD	TYPE	RESET	DESCRIPTION				
15-10	RESERVED	R/W	1Ah	RESERVED				
9	ref_mux_src	R/W	0h	Reference mux control signal source.				
				0h = Pin				
				1h = ref_mux bit-field				
8	ref_mux	R/W	0h	Reference mux bit override.				
				0h = XIN				
				1h = REF				
7-4	gpio4_input_sel	R/W	3h	GPIO4 input signal select. Do not choose the same signal on				
				gpio1_input_sel.				
				2h = OE				
				4h = OE1				
				5h = OE2				
				6h = OE3				
				7h = OE4				
3-0	gpio1_input_sel	R/W	2h	GPIO1 input signal select.Do not choose the same signal on				
				gpio4_input_sel.				
				2h = OE				
				4h = OE1				
				5h = OE2				
				6h = OE3				
				7h = OE4				
	1	-	-	1				



10.1.3 GENERIC2 Register (Address = 2h) [reset = 53h]

GENERIC2 is shown in Figure 10-3 and described in Table 10-5.

Return to Summary Table.

Figure 10-3. GENERIC2 Register

15	14	13	12	11	10	9	8	
RESERVED	RESERVED	RESE	ERVED		gpio0_output_sel			
R/W-0h	R/W-0h	RΛ	V-0h	R/W-0h				
7	6	5	4	3	2	1	0	
	gpio4_o	utput_sel			gpio1_ou	tput_sel		
R/W-5h					R/W	-3h		

Table 10-5. GENERIC2 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-12	RESERVED	R/W	0h	Reserved.
11-8	gpio0_output_sel	R/W	0h	GPIO0, Pin 8, output select ,
				0h = PLL_LOCK
				1h = XTAL_OSC
				2h = CAL_DONE
				3h = CONF_DONE
				4h = SYNC_DONE
				5h = EEPROM_BUSY
				6h = EEPROM_Y12
				7h = EEPROM_M12
				8h = I2C_LSB
				9h = CLK_FSM
				Ah = CLK_PFD_REF
				Bh = CLK_PFD_FB
				Ch = BUF_SYNC
				Dh = BUF_SCL
				Eh = BUF_SDA

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Table 10-5. GENERIC2 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION (continued)
7-4	gpio4_output_sel	R/W	5h	GPIO4 , output select ,
				0h = PLL_LOCK
				1h = XTAL_OSC
				2h = CAL_DONE
				3h = CONF_DONE
				4h = SYNC_DONE
				5h = EEPROM_BUSY
				6h = EEPROM_Y12
				7h = EEPROM_M12
				8h = I2C_LSB
				9h = CLK_FSM
				Ah = CLK_PFD_REF
				Bh = CLK_PFD_FB
				Ch = BUF_SYNC
				Dh = BUF_SCL
				Eh = BUF_SDA
3-0	gpio1_output_sel	R/W	3h	GPIO1 , output select ,
				0h = PLL_LOCK
				1h = XTAL_OSC
				2h = CAL_DONE
				3h = CONF_DONE
				4h = SYNC_DONE
				5h = EEPROM_BUSY
				6h = EEPROM_Y12
				7h = EEPROM_M12
				8h = I2C_LSB
				9h = CLK_FSM
				Ah = CLK_PFD_REF
				Bh = CLK_PFD_FB
				Ch = BUF_SYNC
				Dh = BUF_SCL
				Eh = BUF_SDA



10.1.4 GENERIC3 Register (Address = 3h) [reset = 0h]

GENERIC3 is shown in Figure 10-4 and described in Table 10-6.

Return to Summary Table.

Figure 10-4. GENERIC3 Register

				-			
15	14	13	12	11	10	9	8
disable_crc	update_crc	nvmcommit	regcommit	regcommit_pag e	RESERVED	RESERVED	RESERVED
R/W-0h	R/WMC-0h	R/WSC-0h	R/WSC-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h
7	6	5	4	3	2	1	0
RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED
R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/WSC-0h	R/WSC-0h	R/W-0h

Table 10-6. GENERIC3 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
		1		
15	disable_crc	R/W	Oh	Disable the CRC computation. However if Page is selected CRC will happen after PoR (power on reset from analog). For example- after the calibration if this bit is set to '1' and apply a soft reset (or reset through pin) the configuration will bypass the CRC computation.
14	update_crc	R/WMC	0h	This is a self clearing register bit. Writing a '1' will cause the recomputation of CRC. The computed CRC can be read from the live CRC (nvmlcrc) register after the status bit nvmbusyh = 0.
13	nvmcommit	R/WSC	0h	Commits contents of the EEPROM page selected by REGCOMMIT_PAGE to internal register. This register will self-clear
12	regcommit	R/WSC	0h	Commits contents of the registers to EEPROM selected by REGCOMMIT_PAGE register. This register will self-clear.
11	regcommit_page	R/W	Oh	Decide which page of EEPROM to use for the Register/NVM commit operations. Note= this register is used only after the initial power-up configuration from EEPROM if any. Once power-up configuration is done with the page chosen by EEPROMSEL the value of this register will be used for subsequent configurations using Register/NVM commit operations. Oh = Page 0 1h = Page 1
10-3	RESERVED	R/W	0h	Reserved
2-1	RESERVED	R/WSC	0h	Reserved
0	RESERVED	R/W	0h	Reserved

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10.1.5 POWER0 Register (Address = 4h) [reset = 54h]

POWER0 is shown in Figure 10-5 and described in Table 10-7.

Return to Summary Table.

Figure 10-5. POWER0 Register



Table 10-7. POWER0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-8	RESERVED	R/W	0h	Reserved.
7	pdn_ch4	R/W	0h	Powers Down CH4 LDO.
				0h = Active
				1h = Power down
6	RESERVED	R/W	1h	Reserved.
5	pdn_ch3	R/W	0h	Powers Down CH3 LDO.
				0h = Active
				1h = Power down
4	RESERVED	R/W	1h	Reserved.
3	pdn_ch2	R/W	0h	Powers Down CH2 LDO.
				0h = Active
				1h = Power down
2	RESERVED	R/W	1h	Reserved.
1	pdn_ch1	R/W	0h	Powers Down CH1 LDO.
				0h = Active
				1h = Power down
0	RESERVED	R/W	0h	Reserved.



10.1.6 POWER1 Register (Address = 5h) [reset = 30h]

POWER1 is shown in Figure 10-6 and described in Table 10-8.

Return to Summary Table.

Figure 10-6. POWER1 Register

		,	9				
15	14	13	12	11	10	9	8
		RESERVED		pdn_pll_vcobuf 2	pdn_pll_vco	pdn_pll_vcobuf	
		R/W-0h		R/W-0h	R/W-0h	R/W-0h	
7	6	5	4	3	2	1	0
pdn_pll_cp	pdn_pll_lockdet	pdn_pll_psfbb	pdn_pll_psfba	RESERVED	pdn_pll_pfd	pdn_pll_psfb	pdn_ref
R/W-0h	R/W-0h	R/W-1h	R/W-1h	R/W-0h	R/W-0h	R/W-0h	R/W-0h

Table 10-8. POWER1 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-11	RESERVED	R/W	0h	Reserved.
10	pdn_pll_vcobuf2	R/W	0h	Power down of VCO buffer LDO.
				0h = Active
				1h = Power down
9	pdn_pll_vco	R/W	0h	Power down of VCO LDO.
				0h = Active
				1h = Power down
8	pdn_pll_vcobuf	R/W	0h	Power down of VCO buffer.
				0h = Active
				1h = Power down
7	pdn_pll_cp	R/W	0h	Power down of charge pump LDO.
				0h = Active
				1h = Power down
6	pdn_pll_lockdet	R/W	0h	Power down of PLL lock detector.
				0h = Active
				1h = Power down
5	pdn_pll_psfbb	R/W	1h	Power down of PLL feedback pre-scaler.
				0h = Active
				1h = Power down
4	pdn_pll_psfba	R/W	1h	Active low enable of prescaler-a. Active (low) during PoR and '1'
				later. 1h = Power Down PFD. 0h = Otherwise.
3	RESERVED	R/W	0h	Reserved.
2	pdn_pll_pfd	R/W	0h	Active low enable of PFD. Inactive (high) till calibration and '0' afterwards. 1h = Power Down PFD. 0h = Otherwise.
1	pdn_pll_psfb	R/W	0h	Active low enable of prescaler. Active (low) during PoR and '1' later. 1h = Powers Down PS, 0h = Otherwise.

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Table 10-8. POWER1 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
0	pdn_ref	R/W	0h	Powers Down Input Path LDO. Kill Switch. Do not use. 1h = PD, 0h =
				Otherwise.



10.1.7 STATUS0 Register (Address = 6h) [reset = 0h]

STATUS0 is shown in Figure 10-7 and described in Table 10-9.

Return to Summary Table.

Figure 10-7. STATUS0 Register

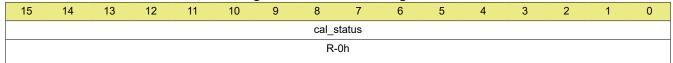


Table 10-9. STATUS0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	cal_status	R	0h	Calibration word.

10.1.8 STATUS1 Register (Address = 7h) [reset = 0h]

STATUS1 is shown in Figure 10-8 and described in Table 10-10.

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Figure 10-8. STATUS1 Register

		,	9				
15	14	13	12	11	10	9	8
	RESE	RVED		lock_det_a	pll_vco_cal_rea dy	nvm_rd_error	nvm_wr_error
	R-	0h		R-0h	R-0h	RC-0h	RC-0h
7	6	5	4	3	2	1	0
rd_error	wr_error	nvmcrcerr	nvmbusy	cal_done	config_done	unlock_s	lock_det
R-0h	R-0h	R-0h	R-0h	R-0h	R-0h	R/WEX-0h	R-0h

Table 10-10. STATUS1 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-12	RESERVED	R	0h	Reserved.
11	lock_det_a	R	0h	Reads the PLL Lock status. 0h: PLL is Unlocked. 1h: PLL is locked.
10	pll_vco_cal_ready	R	0h	VCO Buffer LDO POR can be read through this register.
9	nvm_rd_error	RC 0h		Occurs when any NVM operation is issued during Read Phase of the NVM. The Read Phase of the NVM includes CRC calculation or a simple read through RD NVM Addr/Data registers from any NVM location or a NVM commit operation.
8	nvm_wr_error	RC	Oh	Occurs when any NVM operation is issued during Write Phase of the NVM. Write Phase of the NVM includes a simple write into any NVM location through WR NVM Addr/Data registers or a Register Commit operation.
7	rd_error	R	0h	Reading using the I2C interface with an address above the address of the last register gives this error.
6	wr_error	R	0h	Writing using the I2C interface with an address above the address of the last register gives this error.
5	nvmcrcerr	R	Oh	NVM CRC Error Indication. The NVMCRCERR bit is set to 1 if a CRC Error has been detected when reading back from on-chip EEPROM during device configuration. This bit will be cleared when NVMCOMMIT is submitted or Update CRC is issued.

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Table 10-10. STATUS1 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
4	nvmbusy	R	Oh	NVM Program Busy Indication. The NVMBUSY bit is 1 during an on-chip EEPROM Erase/Program cycle. While NVMBUSY is 1 the on-chip EEPROM cannot be accessed. When the NVM operation is completed this bit will be cleared. NVM related operations are REGcommit NVMcommit CRC calculation or simple Read/Write through RD/WR NVM.
3	cal_done	R	Oh	1h = Calibration (Two rounds of Amplitude followed by calibration) is done.
2	config_done	R	Oh	1 h = Configuration (CRC Check followed by transfer of EEPROM to registers) is done.
1	unlock_s	R/WEX	Oh	Lock Detect Sticky Bit. This indicates the loss of lock of the PLL and this is cleared only by recalibration or a hard reset through RESETN/SYNC pin Oh = locked 1h = unlocked
0	lock_det	R	0h	When the calibration is done frequency may or may not be locked. 1h = Frequency is locked. 0h = Otherwise 0h = unlocked 1h = locked

10.1.9 STATUS2 Register (Address = 8h) [reset = 0h]

STATUS2 is shown in Figure 10-9 and described in Table 10-11.

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Figure 10-9. STATUS2 Register

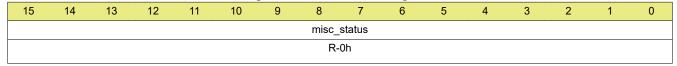


Table 10-11. STATUS2 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	misc_status	R	0h	Miscellaneous status word.

10.1.10 STATUS3 Register (Address = 9h) [reset = 0h]

STATUS3 is shown in Figure 10-10 and described in Table 10-12.

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Figure 10-10. STATUS3 Register

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
nvmlcrc															
R-0h															

Table 10-12. STATUS3 Register Field Descriptions

BIT	FIELD	TYPE RESET		DESCRIPTION
15-0	nvmlcrc	R	0h	The NVMLCRC register holds the Live CRC byte that has been
				calculated while reading on-chip EEPROM.

10.1.11 EEPROM0 Register (Address = Ah) [reset = 0h]

EEPROM0 is shown in Figure 10-11 and described in Table 10-13.

Return to Summary Table.

Figure 10-11. EEPROM0 Register

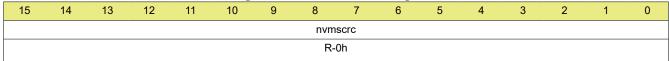


Table 10-13. EEPROM0 Register Field Descriptions

				•				
BIT	FIELD	TYPE	RESET	DESCRIPTION				
15-0	nvmscrc	R	0h	Stored CRC value. This value is used to compare with the computed				
				CRC and to update the CRC Status bit				

10.1.12 EEPROM1 Register (Address = Bh) [reset = 0h]

EEPROM1 is shown in Figure 10-12 and described in Table 10-14.

Return to Summary Table.

Figure 10-12. EEPROM1 Register

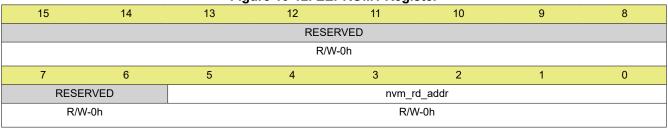


Table 10-14. EEPROM1 Register Field Descriptions

В	IT	FIELD	TYPE	RESET	DESCRIPTION
15	5-6	RESERVED	R/W	0h	Reserved.
5	-0	nvm_rd_addr	R/W	Oh	Writing an address into the NVM WR Address starts the read loop. This register will contain the data read from the EEPROM at the address provided by the NVM WR Address. The address is auto-incremented and subsequent read from the NVM RD Data register will give the data from the next EEPROM location.

10.1.13 EEPROM2 Register (Address = Ch) [reset = 0h]

EEPROM2 is shown in Figure 10-13 and described in Table 10-15.

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Figure 10-13. EEPROM2 Register

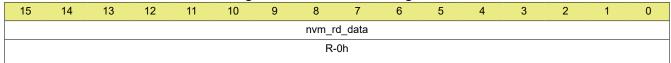


Table 10-15. EEPROM2 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	nvm_rd_data	R	Oh	Reading from this register will return the data present at the EEPROM from the immediate next address location than what was programmed in the NVM RD Address register since writing into NVM RD Address register already returned the data from EEPROM from the written address. Subsequent read from this register will cause the address to be auto-incremented and cause a read from the next EEPROM location.

10.1.14 EEPROM3 Register (Address = Dh) [reset = 0h]

EEPROM3 is shown in Figure 10-14 and described in Table 10-16.

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Figure 10-14. EEPROM3 Register



Table 10-16. EEPROM3 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-6	RESERVED	R/W	0h Reserved.	
5-0	nvm_wr_addr	R/W	0h	Writing an address into the NVM WR Address starts the write loop. But Writing a data into the NVM WR Data register will program the EEPROM with that data at the address provided by writing into NVM WR Address initially.



10.1.15 EEPROM4 Register (Address = Eh) [reset = 0h]

EEPROM4 is shown in Figure 10-15 and described in Table 10-17.

Return to Summary Table.

Figure 10-15. EEPROM4 Register

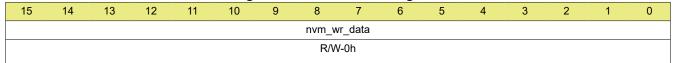


Table 10-17. EEPROM4 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	nvm_wr_data	R/W	0h	Writing a data into this register will program the EEPROM with the written data at the address given by NVM WR Address. Subsequent write into this register will cause the address to be auto-incremented and cause a program at the next EEPROM location.

10.1.16 STARTUP0 Register (Address = Fh) [reset = 37h]

STARTUP0 is shown in Figure 10-16 and described in Table 10-18.

Return to Summary Table.

Figure 10-16. STARTUP0 Register

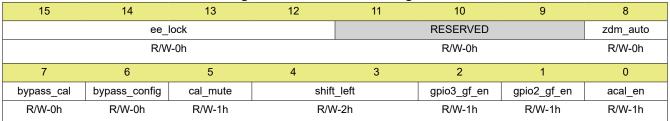


Table 10-18. STARTUP0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-12	ee_lock	R/W	0h	Locks EEPROM for regcommit and EEPROM write operations. To unlock, write 5h, any other value to lock.
11-9	RESERVED	R/W	0h	Reserved.
8	zdm_auto	R/W	0h	Setting this bit 1 will allow state machine to control the value of pll_ndiv and pll_psfb internally in Normal/ZDM mode of calibration. If set 0 the user has to manually program the pll_ndiv and pll_psfb
7	bypass_cal	R/W	0h	Bypass the calibration. By default two rounds of calibrations (AC followed by FC) will be done. Setting this bit to 1 will bypass the calibration.
6	bypass_config	R/W	0h	Bypass the configuration. Note that on PoR this bit is zero and hence configuration will happen. However after the first configuration this bit can be set and apply the soft/pin reset so that configuration will be bypassed.
5	cal_mute	R/W	1h	Mute the output during the calibration. 0h = Outputs stay active 1h = Outputs muted

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Table 10-18. STARTUP0 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION (CONTAINED A)
4-3	shift_left	R/W	2h	Divide the ref clock (PFD clock) during calibration by 2 to the power of value 0h = 1
				1h = 2 2h = 4
				3h = 8
2	gpio3_gf_en	R/W	1h	Enable the glitch filter for SCL, GPIO3.
				0h = Disabled 1h = Enabled
1	gpio2_gf_en	R/W	1h	Enable the glitch filter for SDA, GPIO2.
				0h = Disabled
				1h = Enabled
0	acal_en	R/W	1h	Enable automatic frequency calibration at power-up or EEPROM reload.
				0h = Disabled
				1h = Enabled

10.1.17 STARTUP1 Register (Address = 10h) [reset = 921Fh]

STARTUP1 is shown in Figure 10-17 and described in Table 10-19.

Return to Summary Table.

Figure 10-17. STARTUP1 Register

15	14	13	12	11	10	9	8
		pll_lock_dly				ac_init_dly	
		R/W-12h				R/W-10h	
7	6	5	4	3	2	1	0
	ac_init_dly				cp_dly		
	R/W-10h				R/W-1Fh		

Table 10-19. STARTUP1 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-11	pll_lock_dly	R/W	12h	Wait time before lock detect goes high after the calibration. Expected value is approximately 1 ms. The actual delay will be 4 × T × {programmed value} where T = 200ns typically.
10-5	ac_init_dly	R/W	10h	Peak detector settlig time, that is, pll_en_peakdet_vco going high to first cross code change. Expected value is 1.6 μs. The actual delay will be 4 × T × {programmed value} where T = 200ns typically.
4-0	cp_dly	R/W	1Fh	Delay from vtune driver enable (pll_en_vtune_drv) going high to peak detector enable (pll_en_peakdet_vco) going high. Expected delay is 200 µs. The actual delay will be 64 × T × {programmed value} where T = 200ns typically.

10.1.18 STARTUP2 Register (Address = 11h) [reset = 6C4h]

STARTUP2 is shown in Figure 10-18 and described in Table 10-20.

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Figure 10-18. STARTUP2 Register

15	14	13	12	11	10	9	8	
RESERVED		switch	h_dly		err_cnt			
R/W-0h		R/W	/-0h	·	R/W-6h			
7	6	5	4	3	2	1	0	
fc_se	tl_dly			ac_cm	o_dly			
R/M	/-3h			R/W-	4h			
I								

Table 10-20. STARTUP2 Register Field Descriptions

	I			
BIT	FIELD	TYPE	RESET	DESCRIPTION
15	RESERVED	R/W	0h	Reserved.
14-11	switch_dly	R/W	0h	Indicates number of digital clocks to wait before SSM clock is turned off after all the active signals are low. Internally scaled up by 2 ⁶ . Digital clock period is 200ns typically.
10-8	err_cnt	R/W	6h	Indicates how long to wait for before declaring lock detect. In PFD clocks period. 0h = 32 1h = 64 2h = 128 3h = 256
7-6	fc_setl_dly	R/W	3h	Delay between two cap codes in terms of REFCLK period. Expected value is 1 µs. The actual delay will be 32 × T × {programmed value} where T is the refclk period.
5-0	ac_cmp_dly	R/W	4h	Delay between successive cross code change. Expected value is 1 µs. The actual delay will be 4 × T × {programmed value} where T = 200ns typically.

10.1.19 REV0 Register (Address = 18h) [reset = 601h]

REV0 is shown in Figure 10-19 and described in Table 10-21.

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Figure 10-19. REV0 Register

		-	.9		•		
15	14	13	12	11	10	9	8
			RESE	RVED			
			R/W	/-6h			
7	6	5	4	3	2	1	0
			rev_	_reg			
			R-	1h			

Table 10-21. REV0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-8	Reserved	R	06h	Reserved

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Table 10-21. REV0 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
7-0	rev_reg	R	1h	Revision ID register.
				1h = CDCl6214



10.1.20 INPUT0 Register (Address = 1Ah) [reset = B14h]

INPUT0 is shown in Figure 10-20 and described in Table 10-22.

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Figure 10-20. INPUT0 Register

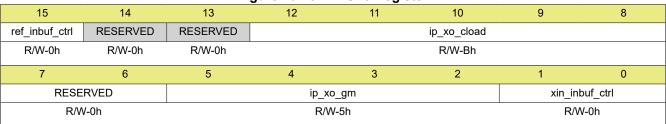


Table 10-22. INPUT0 Register Field Descriptions

Table 10 221 Htt 010 Hogister Flora 2000 i parent							
BIT	FIELD	TYPE	RESET	DESCRIPTION			
15	ref_inbuf_ctrl	R/W	0h	Reference input buffer select.			
				0h = LVCMOS			
				1h = AC-Differential			
14	RESERVED	R/W	0h	RESERVED			
13	RESERVED	R/W	0h	RESERVED			



Table 10-22. INPUT0 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
12-8	ip_xo_cload	R/W	Bh	Selects load cap for XO (up to 9 pF) in 5 bit binary selection). Step size is about 200 fF.
				0h = 3.0 pF
				1h = 3.2 pF
				2h = 3.4 pF
				3h = 3.6 pF
				4h = 3.8 pF
				5h = 4.0 pF
				6h = 4.2 pF
				7h = 4.4 pF
				8h = 4.6 pF
				9h = 4.8 pF
				Ah = 5.0 pF
				Bh = 5.2 pF
				Ch = 5.4 pF
				Dh = 5.6 pF
				Eh = 5.8 pF
				Fh = 6.0 pF
				10h = 6.2 pF
				11h = 6.4 pF
				12h = 6.5 pF
				13h = 6.7 pF
				14h = 6.9 pF
				15h = 7.1 pF
				16h = 7.3 pF
				17h = 7.5 pF
				18h = 7.7 pF
				19h = 7.9 pF
				1Ah = 8.1 pF
				1Bh = 8.3 pF
				1Ch = 8.5 pF
				1Dh = 8.7 pF
				1Eh = 8.9 pF
				1Fh = 9.0 pF
7-6	RESERVED	R/W	0h	RESERVED



Table 10-22. INPUT0 Register Field Descriptions (continued)

BIT			RESET	DESCRIPTION
		R/W	5h	
5-2	ip_xo_gm	IK/VV	311	Tune bias current for XO. Gm programmability. Typical values:
				0h = Disabled
				1h = 14 μA
				2h = 29 μA
				3h = 44 μA
				4h = 59 μA
				5h = 148 μA
				6h = 295 μA
				7h = 443 μA
				8h = 591 μA
				9h = 884 μA
				Ah = 1177 μA
				Bh = 1468 μA
				Ch = 1758 μA
1-0	xin_inbuf_ctrl	R/W	0h	Input buffer select.
				0h = XO
				1h = CMOS
				2h = DIFF

10.1.21 INPUT1 Register (Address = 1Bh) [reset = 0h]

INPUT1 is shown in Figure 10-21 and described in Table 10-23.

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Figure 10-21. INPUT1 Register

			•					
15	14	13	12	11	10	9	8	
RESERVED	ip_byp_en_ch4	ip_byp_en_ch3	ip_byp_en_ch2	ip_byp_en_ch1	ip_byp_en_y0	ip_byp_mux	ip_rst_rdiv	
R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	
7	6	5	4	3	2	1	0	
ip_rdiv								
R/W-0h								

Table 10-23. INPUT1 Register Field Descriptions

Table 10-23. INPUTT Register Fleid Descriptions						
BIT	FIELD	TYPE	RESET	DESCRIPTION		
15	RESERVED	R/W	0h	RESERVED		
14	ip_byp_en_ch4	R/W	Oh	Bypass path buffer enable for CH4. This is required to drive a bypass signal using ch4_iod_mux. 0h = disabled 1h = enabled		
13	ip_byp_en_ch3	R/W	Oh	Bypass path buffer enable for CH3. This is required to drive a bypass signal using ch3_iod_mux. Oh = disabled 1h = enabled		
12	ip_byp_en_ch2	R/W	Oh	Bypass path buffer enable for CH2. This is required to drive a bypass signal using ch2_iod_mux. Oh = disabled 1h = enabled		
11	ip_byp_en_ch1	R/W	Oh	Bypass path buffer enable for CH1. This is required to drive a bypass signal using ch1_iod_mux. Oh = disabled 1h = enabled		
10	ip_byp_en_y0	R/W	0h	Enable input clock to come out on Y0 buffer.		
9	ip_byp_mux	R/W	Oh	Selects Y0 clock between "REF_CLK" and "PFD_CLK". 0h = REF 1h = PFD		
8	ip_rst_rdiv	R/W	0h	Resets flops in ref divider. Active (high) during power on reset or SWRST or pin reset and inactive afterwards.		

Table 10-23. INPUT1 Register Field Descriptions (continued)

					- 1014 = 0001 pilotto (0011411404)
	BIT	FIELD	TYPE	RESET	DESCRIPTION
	7-0	ip_rdiv	R/W	0h	Reference clock divider. 0 = Doubler ON, 1 = /1, 2 = /2. and so forth.
					0h = x2
					1h = /1
					2h = /2
					3h = /3
					4h = /4
					5h = /5
					FFh = /255
- 1					

10.1.22 INPUT_DBG0 Register (Address = 1Ch) [reset = 0h]

INPUT_DBG0 is shown in Figure 10-22 and described in Table 10-24.

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Figure 10-22. INPUT_DBG0 Register

15	14	13	12	11	10	9	8
RES	ERVED	RESERVED			RESERVED		
R/	W-0h	R/W-0h			R/W-0h		
7	6	5	4	3	2	1	0
RES	ERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED	RESERVED
R/	W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h

Table 10-24. INPUT_DBG0 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-6	RESERVED	R/W	0h	RESERVED.
5	RESERVED	R/W	0h	RESERVED
4	RESERVED	R/W	0h	RESERVED
3	RESERVED	R/W	0h	RESERVED
2	RESERVED	R/W	0h	RESERVED
1	RESERVED	R/W	0h	RESERVED
0	RESERVED	R/W	0h	RESERVED

10.1.23 PLL0 Register (Address = 1Dh) [reset = Ch]

PLL0 is shown in Figure 10-23 and described in Table 10-25.

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Figure 10-23. PLL0 Register

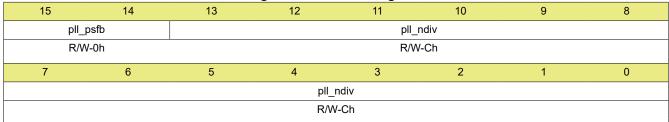


Table 10-25. PLL0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-14	pll_psfb	R/W	0h Programming bits for PLL feedback pre-scaler.	
				0h = /4
				1h = /5
				2h = /6
13-0	pll_ndiv	R/W	Ch	Feedback divider, must be at least 6h.



10.1.24 PLL1 Register (Address = 1Eh) [reset = 5140h]

PLL1 is shown in Figure 10-24 and described in Table 10-26.

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Figure 10-24. PLL1 Register

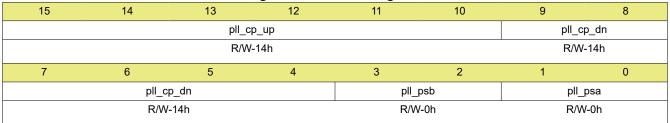


Table 10-26. PLL1 Register Field Descriptions

15-10 pll_cp_up R/W 14h Programming bits for up current of CP. 0h = 0.0 mA 1h = 0.1 mA 2h = 0.2 mA	
1h = 0.1 mA	
2h = 0.2 mA	
3h = 0.3 mA	
[]	
1Fh = 3.1 mA	
37h = 3.2 mA	
38h = 3.3 mA	
[]	
3Dh = 3.8 mA	
3Eh = 3.9 mA	
3Fh = 4.0 mA	
9-4 pll_cp_dn R/W 14h Programming bits for down current of CP.	
0h = 0.0 mA	
1h = 0.1 mA	
2h = 0.2 mA	
3h = 0.3 mA	
[]	
1Fh = 3.1 mA	
37h = 3.2 mA	
38h = 3.3 mA	
[]	
3Dh = 3.8 mA	
3Eh = 3.9 mA	
3Fh = 4.0 mA	

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Table 10-26. PLL1 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
3-2	pll_psb	R/W	0h	Programming bits for pre-scaler B.
				0h = /4
				1h = /5
				2h = /6
1-0	pll_psa	R/W	0h	Programming bits for pre-scaler A.
				0h = /4
				1h = /5
				2h = /6



10.1.25 PLL2 Register (Address = 1Fh) [reset = 1E72h]

PLL2 is shown in Figure 10-25 and described in Table 10-27.

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Figure 10-25. PLL2 Register

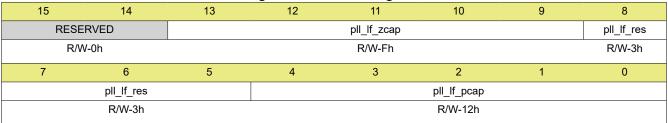


Table 10-27. PLL2 Register Field Descriptions

BIT	FIELD	TYPE	RESET	ster Field Descriptions DESCRIPTION
15-14	RESERVED	R/W	0h	
				RESERVED.
13-9	pll_lf_zcap	R/W	Fh	Programming bits of cap value of zero of loop-filter.
				0h = 000 pF
				1h = 030 pF
				2h = 060 pF
				3h = 090 pF
				4h = 120 pF
				5h = 150 pF
				6h = 180 pF
				7h = 210 pF
				8h = 240 pF
				9h = 270 pF
				Ah = 300 pF
				Bh = 330 pF
				Ch = 360 pF
				Dh = 390 pF
				Eh = 420 pF
				Fh = 450 pF
				10h = 480 pF
				11h = 510 pF
				12h = 540 pF
				13h = 570 pF
				14h = 600 pF

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Table 10-27. PLL2 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
8-5	pll_lf_res	R/W	3h	Programming bits of res value of zero of loop-filter.
				0h = open k $Ω$
				1h = 00.5 kΩ
				2h = 01.5 kΩ
				3h = 02.5 kΩ
				4h = 03.5 kΩ
				5h = 04.5 kΩ
				6h = 05.5 kΩ
				7h = 06.5 kΩ
				 8h = 07.5 kΩ
				9h = 08.5 kΩ
				Ah = 09.5 kΩ
				 Bh = 10.5 kΩ
				Ch = 11.5 kΩ
4-0	pll_lf_pcap	R/W	12h	Programming bits of cap value of pole of loop-filter.
				0h = 00.0 pF
				1h = 00.5 pF
				2h = 01.5 pF
				3h = 02.5 pF
				4h = 03.5 pF
				5h = 04.5 pF
				6h = 05.5 pF
				7h = 06.5 pF
				8h = 07.5 pF
				9h = 08.5 pF
				Ah = 09.5 pF
				Bh = 10.5 pF
				Ch = 11.5 pF
				Dh = 12.5 pF
				Eh = 13.5 pF
				Fh = 14.5 pF
				10h = 15.5 pF
				11h = 16.5 pF
				12h = 17.5 pF
				13h = 18.5 pF
				14h = 19.5 pF
		_		



10.1.26 PLL4 Register (Address = 21h) [reset = 7h]

PLL4 is shown in Figure 10-26 and described in Table 10-28.

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Figure 10-26. PLL4 Register

			•	-			
15	14	13	12	11	10	9	8
RESERVED		RESERVED			RESERVED		RESERVED
R/W-0h		R/W-0h			R/W-0h		R/W-0h
7	6	5	4	3	2	1	0
RESERVED	pll_pfd	_dly_ctrl	ŗ	pll_lockdet_window		pll_lockdet_wait	
R/W-0h	R/\	V-0h		R/W-1h	·	R/V	V-3h

Table 10-28. PLL4 Register Field Descriptions

	Table 10-28. PLL4 Register Field Descriptions								
BIT	FIELD	TYPE	RESET	DESCRIPTION					
15-7	RESERVED	R/W	0h	Reserved.					
6-5	pll_pfd_dly_ctrl	R/W	0h	Programming of PFD reset delay. In PFD period.					
				0h = 2					
				1h = 6					
				2h = 10					
				3h = 14					
4-2	pll_lockdet_window	R/W	1h	Programmability of PFD input and output time window for lock					
				detect.					
				0h = disabled					
				1h = typical 1.4 ns					
				2h = typical 2.6 ns					
				3h = typical 3.9 ns					
				4h = typical 5.2 ns					
				5h = typical 6.4 ns					
				6h = typical 7.6 ns					
				7h = typical 8.9 ns					
1-0	pll_lockdet_wait	R/W	3h	Programmability of analog lock detect timer. In PFD cycles					
				0h = 1					
				1h = 16					
				2h = 64					
				3h = 128					

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10.1.27 CH1_CTRL0 Register (Address = 23h) [reset = 8000h]

CH1_CTRL0 is shown in Figure 10-27 and described in Table 10-29.

Return to Summary Table.

Figure 10-27. CH1_CTRL0 Register

	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
RESERVED																
								R/WEX	(-8000h							

Table 10-29. CH1_CTRL0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	RESERVED	R/WEX	8000h	RESERVED

10.1.28 CH1_CTRL1 Register (Address = 24h) [reset = 0h]

CH1_CTRL1 is shown in Figure 10-28 and described in Table 10-30.

Return to Summary Table.

Figure 10-28. CH1_CTRL1 Register

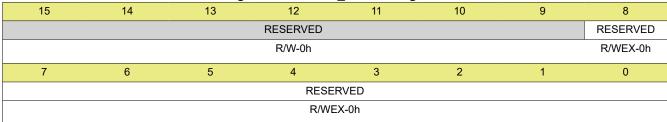


Table 10-30. CH1_CTRL1 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-9	RESERVED	R/W	0h	RESERVED.
8-0	RESERVED	R/WEX	0h	RESERVED.

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10.1.29 CH1_CTRL2 Register (Address = 25h) [reset = 8003h]

CH1_CTRL2 is shown in Figure 10-29 and described in Table 10-31.

Return to Summary Table.

Figure 10-29. CH1_CTRL2 Register

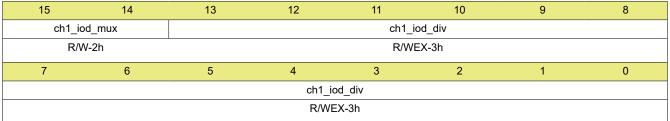


Table 10-31. CH1_CTRL2 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-14	ch1_iod_mux	R/W	2h	Input Clock selection for IOD.
				0h = PSA
				1h = PSB
				3h = REF
13-0	ch1_iod_div	R/WEX	3h	IOD Division Value. 0h = Powers Down, Output=Input/IOD_DIV

10.1.30 CH1_CTRL3 Register (Address = 26h) [reset = 9h]

CH1_CTRL3 is shown in Figure 10-30 and described in Table 10-32.

Return to Summary Table.

Figure 10-30. CH1_CTRL3 Register

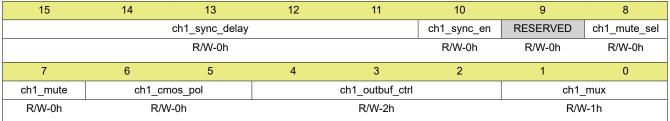


Table 10-32. CH1_CTRL3 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-11	ch1_sync_delay	R/W	0h	Sync Delay cycles of IOD Input Clock. One cycle is a period of the selected pre-scaler clock.
10	ch1_sync_en	R/W	0h	Enables SYNC for the channel.
				0h = Disabled
				1h = Enabled
9	RESERVED	R/W	0h	Reserved.
8	ch1_mute_sel	R/W	0h	Mute selection for Output Channel.
				0h = P=L N=H
				1h = P=H N=L
7	ch1_mute	R/W	0h	To mute the output on this channel.
				0h = Un-mutes the output. 1h = mutes the output.
4-2	ch1_outbuf_ctrl	R/W	2h	Select the output buffer format.
				0h = disabled
				1h = LVDS (1)
				2h = HCSL
				3h = CML
				4h = LVPECL
1-0	ch1_mux	R/W	1h	Output Clock Selection.
				1h = CH1
				2h = CH2

⁽¹⁾ For DC-connection program chx_lvds_cmtrim_inc = 0 and ch[4:1]_1p8vdet in Table 10-53 and Table 10-52 accordingly.

10.1.31 CH1_CTRL4 Register (Address = 27h) [reset = 679h]

CH1_CTRL4 is shown in Figure 10-31 and described in Table 10-33.

Return to Summary Table.

Figure 10-31. CH1_CTRL4 Register

				_			
15	14	13	12	11	10	9	8
RESERVED	RESERVED	RESERVED	RESERVED		RESERVED		RESERVED
R/W-0h	R/W-0h	R/W-0h	R/W-0h		R/W-3h		R/W-0h
7	6	5	4	3	2	1	0
RESE	RVED	RESE	RESERVED		RESERVED	RESERVED	ch1_glitchless_ en
R/W	R/W-1h R/W-3h		R/W-1h	R/W-0h	R/W-0h	R/W-1h	

Table 10-33. CH1_CTRL4 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-12	RESERVED	R/W	0h	RESERVED
11-9	RESERVED	R/W	3h	RESERVED
8	RESERVED	R/W	0h	RESERVED
7-6	RESERVED	R/W	1h	RESERVED
5-4	RESERVED	R/W	3h	RESERVED
3	RESERVED	R/W	1h	RESERVED
2	RESERVED	R/W	0h	RESERVED
1	RESERVED	R/W	0h	RESERVED
0	ch1_glitchless_en	R/W	1h	Enables Glitchless switching for Output Channel.
				0h = Immediate
				1h = Glitchless

10.1.32 CH1_CTRL5 Register (Address = 28h) [reset = 8h]

CH1_CTRL5 is shown in Figure 10-32 and described in Table 10-34.

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Figure 10-32. CH1_CTRL5 Register

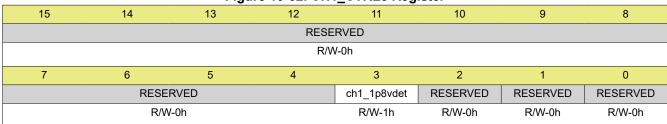


Table 10-34. CH1_CTRL5 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-4	RESERVED	R/W	0h	RESERVED.



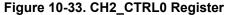
Table 10-34. CH1_CTRL5 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
3	ch1_1p8vdet	R/W	1h	Specify supply on the channel.
				0h = 2.5 V or 3.3 V
				1h = 1.8 V
2-0	RESERVED	R/W	0h	RESERVED

10.1.33 CH2_CTRL0 Register (Address = 29h) [reset = 8000h]

CH2_CTRL0 is shown in Figure 10-33 and described in Table 10-35.

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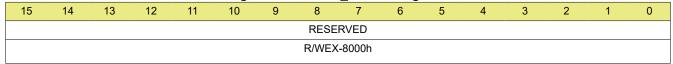


Table 10-35. CH2_CTRL0 Register Field Descriptions

14516 10 001 0112_0 11420 110glotter 1 1014 2 00011ption								
Bit	Field	Туре	Reset	Description				
15-0	RESERVED	R/WEX	8000h	RESERVED				



10.1.34 CH2_CTRL1 Register (Address = 2Ah) [reset = 0h]

CH2_CTRL1 is shown in Figure 10-34 and described in Table 10-36.

Return to Summary Table.

Figure 10-34. CH2_CTRL1 Register

		9		9					
15	14	13	12	11	10	9	8		
	RESERVED								
	R/W-0h								
7	6	5 4 3 2 1					0		
			RESER	RVED					
			R/WE	X-0h					

Table 10-36. CH2_CTRL1 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-9	RESERVED	R/W	0h	RESERVED.
8-0	RESERVED	R/WEX	0h	RESERVED.

10.1.35 CH2_CTRL2 Register (Address = 2Bh) [reset = 0h]

CH2_CTRL2 is shown in Figure 10-35 and described in Table 10-37.

Return to Summary Table.

Figure 10-35. CH2 CTRL2 Register

		9.			.0.0.		
15	14	13	12	11	10	9	8
ch2_ioc	d_mux			ch2_id	od_div		
R/W	'-0h			R/WE	X-0h		
7	6	5	4	3	2	1	0
			ch2_io	d_div			
			R/WE	X-0h			

Table 10-37. CH2_CTRL2 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-14	ch2_iod_mux	R/W	0h Input Clock selection for IOD.	
				0h = PSA
				1h = PSB
				3h = REF
13-0	ch2_iod_div	R/WEX	0h	IOD Division Value. 0h = Powers Down, Output = Input/IOD_DIV

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10.1.36 CH2_CTRL3 Register (Address = 2Ch) [reset = 8h]

CH2_CTRL3 is shown in Figure 10-36 and described in Table 10-38.

Return to Summary Table.

Figure 10-36. CH2_CTRL3 Register

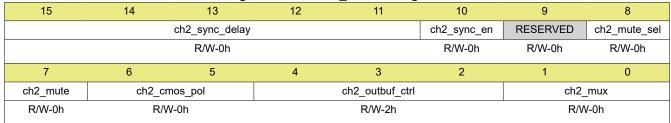


Table 10-38. CH2_CTRL3 Register Field Descriptions

FIELD	TYPE	RESET	DESCRIPTION
ch2_sync_delay	R/W	0h	Sync Delay cycles of IOD Input Clock. One cycle is a period of the selected pre-scaler clock.
ch2_sync_en	R/W	0h	Enables SYNC for the channel.
			0h = Disabled
			1h = Enabled
RESERVED	R/W	0h	RESERVED.
ch2_mute_sel	R/W	0h	Mute selection for Output Channel.
			0h = P=L N=H
			1h = P=H N=L
ch2_mute	R/W	0h	To mute the output on this channel.
			0h = Un-mutes the output. 1h = mutes the output.
ch2_cmos_pol	R/W	0h	programmability of output CMOS buffer polarity.
			0h = P+ N+
			1h = P+ N-
			2h = P- N+
			3h = P- N-
ch2_outbuf_ctrl	R/W	2h	Select the output buffer format.
			0h = disabled
			1h = LVDS ⁽¹⁾
			2h = HCSL
			3h = CML
			4h = LVPECL
			5h = CMOSPN
			6h = CMOSP
			7h = CMOSN
	ch2_sync_delay ch2_sync_en RESERVED ch2_mute_sel ch2_mute ch2_cmos_pol	FIELD TYPE ch2_sync_delay R/W ch2_sync_en R/W RESERVED R/W ch2_mute_sel R/W ch2_mute R/W ch2_cmos_pol R/W	FIELD TYPE RESET ch2_sync_delay R/W 0h ch2_sync_en R/W 0h RESERVED R/W 0h ch2_mute_sel R/W 0h ch2_mute R/W 0h ch2_mute R/W 0h ch2_cmos_pol R/W 0h



Table 10-38. CH2_CTRL3 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION				
1-0	ch2_mux	R/W	0h	Output Clock Selection.				
				0h = CH1				
				1h = CH2				
				2h = CH3				
		BIT FIELD	BIT FIELD TYPE	BIT FIELD TYPE RESET 1-0 ch2_mux R/W 0h				

⁽¹⁾ For DC-connection program chx_lvds_cmtrim_inc = 0 and ch[4:1]_1p8vdet in Table 10-53 and Table 10-52 accordingly.

10.1.37 CH2_CTRL4 Register (Address = 2Dh) [reset = 71h]

CH2_CTRL4 is shown in Figure 10-37 and described in Table 10-39.

Return to Summary Table.

Figure 10-37. CH2 CTRL4 Register

		•					
15	14	13	12	11	10	9	8
RESERVED	RESERVED	RESERVED	RESERVED		RESERVED		RESERVED
R/W-0h	R/W-0h	R/W-0h	R/W-0h		R/W-0h		R/W-0h
7	6	5	4	3	2	1	0
RESE	RVED	RESE	RESERVED		RESERVED	RESERVED	ch2_glitchless_ en
R/W	R/W-1h R/W-3h		/-3h	R/W-0h	R/W-0h	R/W-0h	R/W-1h

Table 10-39. CH2_CTRL4 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-12	RESERVED	R/W	0h	RESERVED
11-8	RESERVED	R/W	0h	RESERVED
7-6	RESERVED	R/W	1h	RESERVED
5-4	RESERVED	R/W	3h	RESERVED
3-1	RESERVED	R/W	0h	RESERVED
0	ch2_glitchless_en	R/W	1h	Enables Glitchless switching for Output Channel.
				0h = Immediate
				1h = Glitchless

10.1.38 CH2_CTRL5 Register (Address = 2Eh) [reset = 8h]

CH2_CTRL5 is shown in Figure 10-38 and described in Table 10-40.

Return to Summary Table.

Figure 10-38. CH2_CTRL5 Register

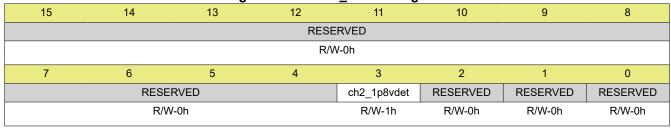


Table 10-40. CH2_CTRL5 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-4	RESERVED	R/W	0h RESERVED.	
3	ch2_1p8vdet	R/W	1h	Specify supply on the channel.
				0h = 2.5 V or 3.3 V
				1h = 1.8 V
2-0	RESERVED	R/W	0h	RESERVED



10.1.39 CH3_CTRL0 Register (Address = 2Fh) [reset = 8000h]

CH3_CTRL0 is shown in Figure 10-39 and described in Table 10-41.

Return to Summary Table.

Figure 10-39. CH3_CTRL0 Register

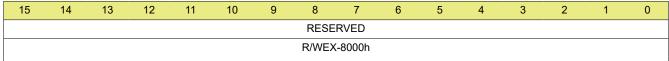


Table 10-41. CH3_CTRL0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	RESERVED	R/WEX	8000h	RESERVED

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10.1.40 CH3_CTRL1 Register (Address = 30h) [reset = 0h]

CH3_CTRL1 is shown in Figure 10-40 and described in Table 10-42.

Return to Summary Table.

Figure 10-40. CH3 CTRL1 Register

		-								
15	14	13	12	11	10	9	8			
	RESERVED									
	R/W-0h									
7	6	5 4 3 2 1								
	RESERVED									
			R/WE	X-0h						

Table 10-42. CH3_CTRL1 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-9	RESERVED	R/W	0h	RESERVED.
8-0	RESERVED	R/WEX	0h	RESERVED

10.1.41 CH3_CTRL2 Register (Address = 31h) [reset = 0h]

CH3_CTRL2 is shown in Figure 10-41 and described in Table 10-43.

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Figure 10-41. CH3_CTRL2 Register

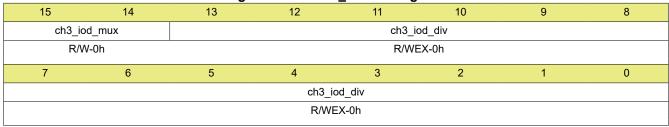


Table 10-43. CH3_CTRL2 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION		
15-14	ch3_iod_mux	R/W	0h	Input Clock selection for IOD.		
				0h = PSA		
				1h = PSB		
				3h = REF		
13-0	ch3_iod_div	R/WEX	0h	IOD Division Value. 0h = Powers Down, Output=Input/IOD_DIV		



10.1.42 CH3_CTRL3 Register (Address = 32h) [reset = 4h]

CH3_CTRL3 is shown in Figure 10-42 and described in Table 10-44.

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Figure 10-42. CH3_CTRL3 Register

15	;	14	13	12	11	10	9	8
ch3_sync_delay						ch3_sync_en	RESERVED	ch3_mute_sel
R/W-0h						R/W-0h	R/W-0h	R/W-0h
7 6 5				4	3	2	1	0
ch3_n	ch3_mute ch3_cmos_pol				ch3_outbuf_ctrl		ch3_	_mux
R/W-0h R/W-0h				R/W-1h		R/V	V-0h	

Table 10-44. CH3 CTRL3 Register Field Descriptions

				Register Field Descriptions
BIT	FIELD	TYPE	RESET	DESCRIPTION
15-11	ch3_sync_delay	R/W	0h	Sync Delay cycles of IOD Input Clock. One cycle is a period of the selected pre-scaler clock.
10	ch3_sync_en	R/W	0h	Enables SYNC for the channel.
				0h = Disabled
				1h = Enabled
9	RESERVED	R/W	0h	RESERVED.
8	ch3_mute_sel	R/W	0h	Mute selection for Output Channel.
				0h = P=L N=H
				1h = P=H N=L
7	ch3_mute	R/W	0h	To mute the output on this channel.
				0h = Un-mutes the output. 1h = mutes the output.
6-5	ch3_cmos_pol	R/W	0h	programmability of output CMOS buffer polarity.
				0h = P+ N+
				1h = P+ N-
				2h = P- N+
				3h = P- N-
4-2	ch3_outbuf_ctrl	R/W	1h	Select the output buffer format.
				0h = disabled
				1h = LVDS ⁽¹⁾
				2h = HCSL
				3h = CML
				4h = LVPECL
				5h = CMOSPN
				6h = CMOSP
				7h = CMOSN
				I

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Table 10-44. CH3_CTRL3 Register Field Descriptions (continued)

BIT	FIELD	_	RESET	DESCRIPTION	
1-0	ch3_mux	R/W	0h	Output Clock Selection.	
				0h = CH2	
				1h = CH3	
				2h = CH4	

(1) For DC-connection program chx_lvds_cmtrim_inc = 0 and ch[4:1]_1p8vdet in Table 10-53 and Table 10-52 accordingly.

10.1.43 CH3_CTRL4 Register (Address = 33h) [reset = 671h]

CH3_CTRL4 is shown in Figure 10-43 and described in Table 10-45.

Return to Summary Table.

Figure 10-43. CH3_CTRL4 Register

				_			
15	14	13	12	11	10	9	8
RESERVED	RESERVED	RESERVED	RESERVED		RESERVED		RESERVED
R/W-0h	R/W-0h	R/W-0h	R/W-0h		R/W-3h		R/W-0h
7	6	5	4	3	2	1	0
RESERVED		RESE	RVED	RESERVED	RESERVED	RESERVED	ch3_glitchless_ en
R/W-1h		R/W	/-3h	R/W-0h	R/W-0h	R/W-0h	R/W-1h

Table 10-45. CH3_CTRL4 Register Field Descriptions

Bit	Field	Туре	Reset	Description
DIL	rieid	туре	Reset	Description
15-12	RESERVED	R/W	0h	RESERVED
11-9	RESERVED	R/W	3h	RESERVED
8	RESERVED	R/W	0h	RESERVED
7-6	RESERVED	R/W	1h	RESERVED
5-4	RESERVED	R/W	3h	RESERVED
3-1	RESERVED	R/W	0h	RESERVED
0	ch3_glitchless_en	R/W	1h	Enables Glitchless switching for Output Channel.
				0h = Immediate
				1h = Glitchless

10.1.44 CH3_CTRL5 Register (Address = 34h) [reset = 8h]

CH3_CTRL5 is shown in Figure 10-44 and described in Table 10-46.

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Figure 10-44. CH3_CTRL5 Register

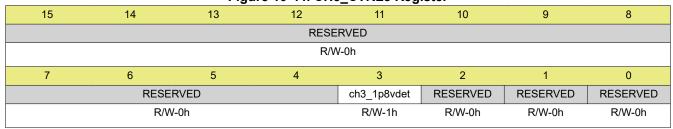


Table 10-46. CH3_CTRL5 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION	
15-4	RESERVED	R/W	0h	RESERVED.	
3	ch3_1p8vdet	R/W	1h	Specify supply on the channel.	
				0h = 2.5 V or 3.3 V	
				1h = 1.8 V	

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Table 10-46. CH3_CTRL5 Register Field Descriptions (continued)

BIT	FIELD	TYPE	RESET	DESCRIPTION
2-0	RESERVED	R/W	0h	RESERVED

10.1.45 CH4_CTRL0 Register (Address = 35h) [reset = 8000h]

CH4_CTRL0 is shown in Figure 10-45 and described in Table 10-47.

Return to Summary Table.

Figure 10-45. CH4_CTRL0 Register

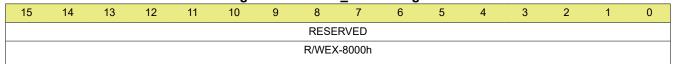


Table 10-47. CH4 CTRL0 Register Field Descriptions

			_	•
Bit	Field	Туре	Reset	Description
15-0	RESERVED	R/WEX	8000h	RESERVED



10.1.46 CH4_CTRL1 Register (Address = 36h) [reset = 0h]

CH4_CTRL1 is shown in Figure 10-46 and described in Table 10-48.

Return to Summary Table.

Figure 10-46. CH4_CTRL1 Register

				9						
15	14	13	12	11	10	9	8			
	RESERVED									
	R/W-0h									
7	6	5	4	3	2	1	0			
	RESERVED									
			R/WE	X-0h						

Table 10-48. CH4_CTRL1 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-9	RESERVED	R/W	0h	RESERVED.
8-0	RESERVED	R/WEX	0h	RESERVED

10.1.47 CH4_CTRL2 Register (Address = 37h) [reset = 0h]

CH4_CTRL2 is shown in Figure 10-47 and described in Table 10-49.

Return to Summary Table.

Figure 10-47. CH4_CTRL2 Register

15	14	13	12	11	10	9	8
ch4_ic	od_mux			ch4_i	od_div		
R/V	V-0h			R/WE	EX-0h		
7	6	5	4	3	2	1	0
			ch4_ic	od_div			
	R/WEX-0h						

Table 10-49. CH4_CTRL2 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-14	ch4_iod_mux	R/W	0h	Input Clock selection for IOD.
				0h = PSA
				1h = PSB
				3h = REF
13-0	ch4_iod_div	R/WEX	0h	IOD Division Value. 0h = Powers Down, Output=Input/IOD_DIV.

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10.1.48 CH4_CTRL3 Register (Address = 38h) [reset = 4h]

CH4_CTRL3 is shown in Figure 10-48 and described in Table 10-50.

Return to Summary Table.

Figure 10-48. CH4_CTRL3 Register

15	14	13	12	11	10	9	8
	ch4_sync_delay					RESERVED	ch4_mute_sel
	R/W-0h				R/W-0h	R/W-0h	R/W-0h
7	6	5	4	3	2	1	0
ch4_mute	4_mute ch4_cmos_pol			ch4_outbuf_ctrl		ch4_	_mux
R/W-0h	RΛ	V-0h		R/W-1h		R/V	V-0h

Table 10-50. CH4_CTRL3 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-11	ch4_sync_delay	R/W	0h	Sync Delay cycles of IOD Input Clock. One cycle is a period of the selected pre-scaler clock.
10	ch4_sync_en	R/W	Oh	Enables SYNC for the channel. 0h = Disabled 1h = Enabled
9	RESERVED	R/W	0h	RESERVED.
8	ch4_mute_sel	R/W	Oh	Mute selection for Output Channel. 0h = P=L N=H 1h = P=H N=L
7	ch4_mute	R/W	0h	To mute the output on this channel. 0h = Un-mutes the output. 1h = mutes the output.
4-2	ch4_outbuf_ctrl	R/W	1h Select the output buffer format. Oh = disabled 1h = LVDS(1) 2h = HCSL 3h = CML 4h = LVPECL	
1-0	ch4_mux	R/W	Oh	Output Clock Selection. 0h = Previous Channel, 1h = Current Channel, 2h = Next Channel, 3h = AGND 0h = CH3 1h = CH4

⁽¹⁾ For DC-connection program chx_lvds_cmtrim_inc = 0 and ch[4:1]_1p8vdet in Table 10-53 and Table 10-52 accordingly.

10.1.49 CH4_CTRL4 Register (Address = 39h) [reset = 71h]

CH4_CTRL4 is shown in Figure 10-49 and described in Table 10-51.

Return to Summary Table.

Figure 10-49. CH4_CTRL4 Register

		•					
15	14	13	12	11	10	9	8
RESERVED	RESERVED	RESERVED	RESERVED		RESERVED		RESERVED
R/W-0h	R/W-0h	R/W-0h	R/W-0h		R/W-0h		R/W-0h
7	6	5	4	3	2	1	0
RESE	RVED	RESERVED		RESERVED	RESERVED	RESERVED	ch4_glitchless_ en
R/W	V-1h	R/W	R/W-3h		R/W-0h	R/W-0h	R/W-1h

Table 10-51. CH4_CTRL4 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-12	RESERVED	R/W	0h	RESERVED
11-8	RESERVED	R/W	0h	RESERVED
7-6	RESERVED	R/W	1h	RESERVED
5-4	RESERVED	R/W	3h	RESERVED
3-1	RESERVED	R/W	0h	RESERVED
0	ch4_glitchless_en	R/W	1h	Enables Glitchless switching for Output Channel.
				0h = Immediate
				1h = Glitchless

10.1.50 CH4_CTRL5 Register (Address = 3Ah) [reset = 8h]

CH4_CTRL5 is shown in Figure 10-50 and described in Table 10-52.

Return to Summary Table.

Figure 10-50. CH4_CTRL5 Register

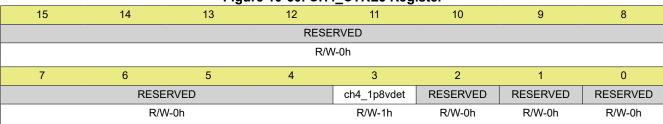


Table 10-52. CH4_CTRL5 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION	
15-4	RESERVED	R/W	0h	RESERVED.	
3	ch4_1p8vdet	R/W	1h	Specify supply on the channel.	
				0h = 2.5 V or 3.3 V	
				1h = 1.8 V	
2-0	RESERVED	R/W	0h	RESERVED	

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10.1.51 CHX_CTRL0 Register (Address = 3Bh) [reset = 61h]

CHX_CTRL0 is shown in Figure 10-51 and described in Table 10-53.

Return to Summary Table.

Figure 10-51. CHX CTRL0 Register

		J -					
15	14	13	12	11	10	9	8
RESERVED	RESERVED	chx_rst	chx_lvds_c	emtrim_inc	chx_lvds_cr	mtrim_dec	chx_diffbuf_ibia s_trim
R/W-0h	R/W-0h	R/W-0h	R/W	′-0h	R/W-	-0h	R/W-3h
7	6	5	4	3	2	1	0
ch	x_diffbuf_ibias_tri	m	chx_lvcmos_drv	RESERVED	ch0_lvcm	os_drv	RESERVED
	R/W-3h		R/W-1h	R/W-0h	R/W-	-0h	R/W-1h

Table 10-53. CHX_CTRL0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-14	RESERVED	R/W	0h	RESERVED
13	chx_rst	R/W	0h	All Channel RST during power up and later. 1h = RST, 0h = Normal.
12-11	chx_lvds_cmtrim_inc	R/W	0h	Increments differential output buffer output common-mode programmability. Use either CHX_LVDS_CMTRIM_INC or CHX_LVDS_CMTRIM_DEC.
10-9	chx_lvds_cmtrim_dec	R/W	0h	Decrements differential output buffer output common-mode programmability. Increment Use either CHX_LVDS_CMTRIM_INC or CHX_LVDS_CMTRIM_DEC.
8-5	chx_diffbuf_ibias_trim	R/W	3h	Differential output buffer tail current programmability.
				Ch = 350 μA
				8h = 400 μA
				4h = 450 μA
				0h = 500 μA
				0h = 500 μA
				1h = 550 μA
				2h = 600 μA
				3h = 650 μA
4	chx_lvcmos_drv	R/W	1h	Adjust CH1 to CH4 LVCMOS driver strength.
				0h = Normal
				1h = Fast
3	RESERVED	R/W	1h	RESERVED
2-1	ch0_lvcmos_drv	R/W	0h	Enable Y0 channel and adjust LVCMOS driver strength.
				0h = Off
				1h = Normal
				3h = Fast
0	RESERVED	R/W	1h	RESERVED



10.1.52 CHX_CTRL1 Register (Address = 3Ch) [reset = 18h]

CHX_CTRL1 is shown in Figure 10-52 and described in Table 10-54.

Return to Summary Table.

Figure 10-52. CHX_CTRL1 Register

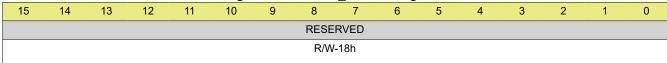


Table 10-54. CHX_CTRL1 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	RESERVED	R/W	18h	RESERVED

10.1.53 CHX_CTRL2 Register (Address = 3Dh) [reset = 1500h]

CHX_CTRL2 is shown in Figure 10-53 and described in Table 10-55.

Return to Summary Table.

Figure 10-53. CHX_CTRL2 Register

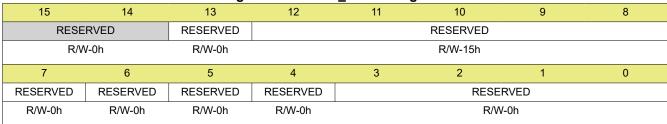


Table 10-55. CHX_CTRL2 Register Field Descriptions

Bit	Field	Туре	Reset	Description
15-13	RESERVED	R/W	0h	RESERVED
12-8	RESERVED	R/W	15h	RESERVED
7-0	RESERVED	R/W	0h	RESERVED



10.1.54 CHX_CTRL3 Register (Address = 3Eh) [reset = 4210h]

CHX_CTRL3 is shown in Figure 10-54 and described in Table 10-56.

Return to Summary Table.

Figure 10-54. CHX_CTRL3 Register

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
							RESE	RVED							
	R/W-4210h														

Table 10-56. CHX_CTRL3 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	RESERVED	R/W	4210h	RESERVED

10.1.55 CHX_CTRL4 Register (Address = 3Fh) [reset = 210h]

CHX_CTRL4 is shown in Figure 10-55 and described in Table 10-57.

Return to Summary Table.

Figure 10-55. CHX_CTRL4 Register

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
							RESE	RVED							
							R/W-	-210h							

Table 10-57. CHX CTRL4 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	RESERVED	R/W	210h	RESERVED

10.1.56 DBG0 Register (Address = 42h) [reset = 200h]

DBG0 is shown in Figure 10-56 and described in Table 10-58.

Return to Summary Table.

Figure 10-56. DBG0 Register

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
							RESE	RVED							
							R/W-	-200h							

Table 10-58. DBG0 Register Field Descriptions

BIT	FIELD	TYPE	RESET	DESCRIPTION
15-0	RESERVED	R/W	200h	RESERVED

10.2 EEPROM Map

The EEPROM is split into a common base page which holds common settings. Then there are two pages for customized settings. Page 0 is selected using EEPROMSEL = Low. Page 1 is selected using EEPROMSEL = High.

The CRC value is stored at the end of page 1 in word 0x3F.

Table 10-59. EEPROM, Base

WORD NO.	SECTION	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
0h	Base	cp_dly[0]	cal_mute	shift_left[1]	shift_left[0]	gpio3_gf_ en	gpio2_gf_ en	acal_en	pdn_pll_v cobuf2	pdn_pll_v co	pdn_pll_v cobuf	pdn_pll_c p	pdn_pll_lo ckdet	pdn_pll_pf d	pdn_pll_p sfb	regcommit _page	resetn_sof t
1h	Base	ac_cmp_d ly[0]	pll_lock_dl y[4]	pll_lock_dl y[3]	pll_lock_dl y[2]	pll_lock_dl y[1]	pll_lock_dl y[0]	ac_init_dl y[5]	ac_init_dl y[4]	ac_init_dl y[3]	ac_init_dl y[2]	ac_init_dl y[1]	ac_init_dl y[0]	cp_dly[4]	cp_dly[3]	cp_dly[2]	cp_dly[1]
2h	Base	0	0	0	0	0	0	err_cnt[2]	err_cnt[1]	err_cnt[0]	fc_setl_dl y[1]	fc_setl_dl y[0]	ac_cmp_d ly[5]	ac_cmp_d ly[4]	ac_cmp_d ly[3]	ac_cmp_d ly[2]	ac_cmp_d ly[1]
3h	Base	pll_pfd_dl y_ctrl[1]	pll_pfd_dl y_ctrl[0]	pll_lockdet _window[2]	pll_lockdet _window[1]	pll_lockdet _window[0]	pll_lockdet _wait[1]	pll_lockdet _wait[0]	0	0	0	0	0	0	0	0	0
4h	Base	0	0	0	1	0	1	0	0	0	0	0	0	0	0	0	0
5h	Base	chx_diffbu f_ibias_tri m[1]	chx_diffbu f_ibias_tri m[0]	chx_lvcmo s_drv	chx_en_c mosslow	0	0	0	1	0	0	0	0	0	1	0	0
6h	Base	0	0	0	0	1	1	0	0	0	0	chx_lvds_ cmtrim_in c[1]	chx_lvds_ cmtrim_in c[0]	chx_lvds_ cmtrim_de c[1]	chx_lvds_ cmtrim_de c[0]	chx_diffbu f_ibias_tri m[3]	chx_diffbu f_ibias_tri m[2]
7h	Base	0	1	0	1	0	0	0	0	0	0	0	0	0	0	0	0
8h	Base	0	0	0	0	1	0	0	0	0	1	1	0	0	0	0	1
9h	Base	1	0	0	0	0	1	0	0	0	0	1	0	0	0	0	1
Ah	Base	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	0
Bh	Base	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

Table 10-60. EEPROM, Page 0

WORD NO.	SECTION	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Ch	Page 0	gpio4_inp ut_sel[3]	gpio4_inp ut_sel[2]	gpio4_inp ut_sel[1]	gpio4_inp ut_sel[0]	gpio1_inp ut_sel[3]	gpio1_inp ut_sel[2]	gpio1_inp ut_sel[1]	gpio1_inp ut_sel[0]	i2c_a0	gpio0_inp ut_sel	gpio4_dir_ sel	gpio1_dir_ sel	gpio0_dir_ sel	zdm_clock sel	zdm_mod e	mode
Dh	Page 0				gpio4_out put_sel[0]					0	1	1	0	1	0	ref_mux_s rc	ref_mux
Eh	Page 0	1	pdn_ch4	1	pdn_ch3	1	pdn_ch2	1	pdn_ch1	1	0	rsrvd_1[1]	rsrvd_1[0]	gpio0_out put_sel[3]	gpio0_out put_sel[2]	gpio0_out put_sel[1]	gpio0_out put_sel[0]
Fh	Page 0	ip_xo_clo ad[2]	ip_xo_clo ad[1]	ip_xo_clo ad[0]	0	0	ip_xo_gm[3]	ip_xo_gm[2]	ip_xo_gm[1]	ip_xo_gm[0]	xin_inbuf_ ctrl[1]	xin_inbuf_ ctrl[0]	zdm_auto	bypass_c al	bypass_c onfig	pdn_pll_p sb	pdn_pll_p sa
10h	Page 0	ip_byp_en _ch3	ip_byp_en _ch2	ip_byp_en _ch1	ip_byp_en _y0	ip_byp_m ux	ip_rdiv[7]	ip_rdiv[6]	ip_rdiv[5]	ip_rdiv[4]	ip_rdiv[3]	ip_rdiv[2]	ip_rdiv[1]	ip_rdiv[0]	ref_inbuf_ ctrl	ip_xo_clo ad[4]	ip_xo_clo ad[3]

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Table 10-60. EEPROM, Page 0 (continued)

WORD									ii, i ago								
NO.	SECTION	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
11h	Page 0	pll_ndiv[1 3]	pll_ndiv[1 2]	pll_ndiv[11]	pll_ndiv[1 0]	pll_ndiv[9]	pll_ndiv[8]	pll_ndiv[7]	pll_ndiv[6]	pll_ndiv[5]	pll_ndiv[4]	pll_ndiv[3]	pll_ndiv[2]	pll_ndiv[1]	pll_ndiv[0]	0	ip_byp_en _ch4
12h	Page 0	pll_cp_up[3]	pll_cp_up[2]	pll_cp_up[1]	pll_cp_up[0]	pll_cp_dn[5]	pll_cp_dn[4]	pll_cp_dn[3]	2]	pll_cp_dn[1]	pll_cp_dn[0]	pll_psb[1]	pll_psb[0]	pll_psa[1]	pll_psa[0]	pll_psfb[1]	pll_psfb[0]
13h	Page 0	pll_lf_zca p[4]	pll_lf_zca p[3]	pll_lf_zca p[2]	pll_lf_zca p[1]	pll_lf_zca p[0]	pll_lf_res[3]	pll_lf_res[2]	pll_lf_res[1]	pll_lf_res[0]	pll_lf_pca p[4]	pll_lf_pca p[3]	pll_lf_pca p[2]	pll_lf_pca p[1]	pll_lf_pca p[0]	pll_cp_up[5]	pll_cp_up[4]
14h	Page 0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
15h	Page 0	ch1_iod_d iv[6]	ch1_iod_d iv[5]	ch1_iod_d iv[4]	ch1_iod_d iv[3]	ch1_iod_d iv[2]	ch1_iod_d iv[1]	ch1_iod_d iv[0]	0	0	0	0	0	0	0	0	0
16h	Page 0	0	0	ch1_outbu f_ctrl[2]	ch1_outbu f_ctrl[1]	ch1_outbu f_ctrl[0]	ch1_mux[1]	ch1_mux[0]	ch1_iod_ mux[1]	ch1_iod_ mux[0]	ch1_iod_d iv[13]	ch1_iod_d iv[12]	ch1_iod_d iv[11]	ch1_iod_d iv[10]	ch1_iod_d iv[9]	ch1_iod_d iv[8]	ch1_iod_d iv[7]
17h	Page 0	0	0	1	0	1	0	0	ch1_glitchl ess_en	ch1_sync _delay[4]	ch1_sync _delay[3]	ch1_sync _delay[2]	ch1_sync _delay[1]	ch1_sync _delay[0]	ch1_sync _en	ch1_mute _sel	ch1_mute
18h	Page 0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	ch1_1p8v det	0
19h	Page 0	ch2_iod_d iv[4]	ch2_iod_d iv[3]	ch2_iod_d iv[2]	ch2_iod_d iv[1]	ch2_iod_d iv[0]	0	0	0	0	0	0	0	0	0	1	0
1Ah	Page 0	ch2_outbu f_ctrl[2]	ch2_outbu f_ctrl[1]	ch2_outbu f_ctrl[0]	ch2_mux[1]	ch2_mux[0]	ch2_iod_ mux[1]	ch2_iod_ mux[0]	ch2_iod_d iv[13]	ch2_iod_d iv[12]	ch2_iod_d iv[11]	ch2_iod_d iv[10]	ch2_iod_d iv[9]	ch2_iod_d iv[8]	ch2_iod_d iv[7]	ch2_iod_d iv[6]	ch2_iod_d iv[5]
1Bh	Page 0	1	0	1	0	0	ch2_glitchl ess_en	ch2_sync _delay[4]	ch2_sync _delay[3]	ch2_sync _delay[2]	ch2_sync _delay[1]	ch2_sync _delay[0]	ch2_sync _en	ch2_mute _sel	ch2_mute	ch2_cmos _pol[1]	ch2_cmos _pol[0]
1Ch	Page 0	0	0	0	0	0	0	0	0	0	0	0	0	ch2_1p8v det	0	0	0
1Dh	Page 0	ch3_iod_d iv[2]	ch3_iod_d iv[1]	ch3_iod_d iv[0]	0	0	0	0	0	0	0	0	0	1	0	0	0
1Eh	Page 0	ch3_outbu f_ctrl[0]	ch3_mux[1]	ch3_mux[0]	ch3_iod_ mux[1]	ch3_iod_ mux[0]	ch3_iod_d iv[13]	ch3_iod_d iv[12]	ch3_iod_d iv[11]	ch3_iod_d iv[10]	ch3_iod_d iv[9]	ch3_iod_d iv[8]	ch3_iod_d iv[7]	ch3_iod_d iv[6]	ch3_iod_d iv[5]	ch3_iod_d iv[4]	ch3_iod_d iv[3]
1Fh	Page 0	0	0	0	ch3_glitchl ess_en	ch3_sync _delay[4]	ch3_sync _delay[3]	ch3_sync _delay[2]	ch3_sync _delay[1]	ch3_sync _delay[0]	ch3_sync _en	ch3_mute _sel	ch3_mute	ch3_cmos _pol[1]	ch3_cmos _pol[0]	ch3_outbu f_ctrl[2]	ch3_outbu f_ctrl[1]
20h	Page 0	0	0	0	0	0	0	0	0	0	0	ch3_1p8v det	1	0	0	1	0
21h	Page 0	ch4_iod_d iv[0]	0	0	0	0	0	0	0	0	0	1	0	0	0	0	0
22h	Page 0	ch4_mux[0]	ch4_iod_ mux[1]	ch4_iod_ mux[0]	ch4_iod_d iv[13]	ch4_iod_d iv[12]	ch4_iod_d iv[11]	ch4_iod_d iv[10]	ch4_iod_d iv[9]	ch4_iod_d iv[8]	ch4_iod_d iv[7]	ch4_iod_d iv[6]	ch4_iod_d iv[5]	ch4_iod_d iv[4]	ch4_iod_d iv[3]	ch4_iod_d iv[2]	ch4_iod_d iv[1]
23h	Page 0	0	ch4_glitchl ess_en	ch4_sync _delay[4]	ch4_sync _delay[3]	ch4_sync _delay[2]	ch4_sync _delay[1]	ch4_sync _delay[0]	ch4_sync _en	ch4_mute _sel	ch4_mute	0	0	ch4_outbu f_ctrl[2]	ch4_outbu f_ctrl[1]	ch4_outbu f_ctrl[0]	ch4_mux[1]
24h	Page 0	0	0	1	1	pll_en_cp	ch0_lvcm os_drv[1]	ch0_lvcm os_drv[0]	1	ch4_1p8v det	1	0	0	1	0	1	0
25h	Page 0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

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Table 10-61. EEPROM, Page 1

							Table I	0-01. EL	PROW,	ı age ı							
WORD NO.	SECTION	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
26h	Page 1	gpio4_inp ut_sel[3]	gpio4_inp ut_sel[2]	gpio4_inp ut_sel[1]	gpio4_inp ut_sel[0]	gpio1_inp ut_sel[3]	gpio1_inp ut_sel[2]	gpio1_inp ut_sel[1]	gpio1_inp ut_sel[0]	i2c_a0	gpio0_inp ut_sel	gpio4_dir_ sel	gpio1_dir_ sel	gpio0_dir_ sel	zdm_clock sel	zdm_mod e	mode
27h	Page 1	gpio4_out put_sel[3]	gpio4_out put_sel[2]	gpio4_out put_sel[1]	gpio4_out put_sel[0]	gpio1_out put_sel[3]	gpio1_out put_sel[2]	gpio1_out put_sel[1]	gpio1_out put_sel[0]	0	1	1	0	1	0	ref_mux_s rc	ref_mux
28h	Page 1	1	pdn_ch4	1	pdn_ch3	1	pdn_ch2	1	pdn_ch1	1	0	rsrvd_1[1]	rsrvd_1[0]	gpio0_out put_sel[3]	gpio0_out put_sel[2]	gpio0_out put_sel[1]	gpio0_out put_sel[0]
29h	Page 1	ip_xo_clo ad[2]	ip_xo_clo ad[1]	ip_xo_clo ad[0]	0	0	ip_xo_gm[3]	ip_xo_gm[2]	ip_xo_gm[1]	ip_xo_gm[0]	xin_inbuf_ ctrl[1]	xin_inbuf_ ctrl[0]	zdm_auto	bypass_c al	bypass_c onfig	pdn_pll_p sb	pdn_pll_p sa
2Ah	Page 1	ip_byp_en _ch3	ip_byp_en _ch2	ip_byp_en _ch1	ip_byp_en _y0	ip_byp_m ux	ip_rdiv[7]	ip_rdiv[6]	ip_rdiv[5]	ip_rdiv[4]	ip_rdiv[3]	ip_rdiv[2]	ip_rdiv[1]	ip_rdiv[0]	ref_inbuf_ ctrl	ip_xo_clo ad[4]	ip_xo_clo ad[3]
2Bh	Page 1	pll_ndiv[1 3]	pll_ndiv[1 2]	pll_ndiv[11]	pll_ndiv[1 0]	pll_ndiv[9]	pll_ndiv[8]	pll_ndiv[7]	pll_ndiv[6]	pll_ndiv[5]	pll_ndiv[4]	pll_ndiv[3]	pll_ndiv[2]	pll_ndiv[1]	pll_ndiv[0]	0	ip_byp_en _ch4
2Ch	Page 1	pll_cp_up[3]	pll_cp_up[2]	pll_cp_up[1]	pll_cp_up[0]	pll_cp_dn[5]	pll_cp_dn[4]	pll_cp_dn[3]	pll_cp_dn[2]	pll_cp_dn[1]	pll_cp_dn[0]	pll_psb[1]	pll_psb[0]	pll_psa[1]	pll_psa[0]	pll_psfb[1]	pll_psfb[0]
2Dh	Page 1	pll_lf_zca p[4]	pll_lf_zca p[3]	pll_lf_zca p[2]	pll_lf_zca p[1]	pll_lf_zca p[0]	pll_lf_res[3]	pll_lf_res[2]	pll_lf_res[1]	pll_lf_res[0]	pll_lf_pca p[4]	pll_lf_pca p[3]	pll_lf_pca p[2]	pll_lf_pca p[1]	pll_lf_pca p[0]	pll_cp_up[5]	pll_cp_up[4]
2Eh	Page 1	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
2Fh	Page 1	ch1_iod_d iv[6]	ch1_iod_d iv[5]	ch1_iod_d iv[4]	ch1_iod_d iv[3]	ch1_iod_d iv[2]	ch1_iod_d iv[1]	ch1_iod_d iv[0]	0	0	0	0	0	0	0	0	0
30h	Page 1	0	0	ch1_outbu f_ctrl[2]	ch1_outbu f_ctrl[1]	ch1_outbu f_ctrl[0]	ch1_mux[1]	ch1_mux[0]	ch1_iod_ mux[1]	ch1_iod_ mux[0]	ch1_iod_d iv[13]	ch1_iod_d iv[12]	ch1_iod_d iv[11]	ch1_iod_d iv[10]	ch1_iod_d iv[9]	ch1_iod_d iv[8]	ch1_iod_d iv[7]
31h	Page 1	0	0	1	0	1	0	0	ch1_glitchl ess_en	ch1_sync _delay[4]	ch1_sync _delay[3]	ch1_sync _delay[2]	ch1_sync _delay[1]	ch1_sync _delay[0]	ch1_sync _en	ch1_mute _sel	ch1_mute
32h	Page 1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	ch1_1p8v det	0
33h	Page 1	ch2_iod_d iv[4]	ch2_iod_d iv[3]	ch2_iod_d iv[2]	ch2_iod_d iv[1]	ch2_iod_d iv[0]	0	0	0	0	0	0	0	0	0	1	0
34h	Page 1	ch2_outbu f_ctrl[2]	ch2_outbu f_ctrl[1]	ch2_outbu f_ctrl[0]	ch2_mux[1]	ch2_mux[0]	ch2_iod_ mux[1]	ch2_iod_ mux[0]	ch2_iod_d iv[13]	ch2_iod_d iv[12]	ch2_iod_d iv[11]	ch2_iod_d iv[10]	ch2_iod_d iv[9]	ch2_iod_d iv[8]	ch2_iod_d iv[7]	ch2_iod_d iv[6]	ch2_iod_d iv[5]
35h	Page 1	1	0	1	0	0	ch2_glitchl ess_en	ch2_sync _delay[4]	ch2_sync _delay[3]	ch2_sync _delay[2]	ch2_sync _delay[1]	ch2_sync _delay[0]	ch2_sync _en	ch2_mute _sel	ch2_mute	ch2_cmos _pol[1]	ch2_cmos _pol[0]
36h	Page 1	0	0	0	0	0	0	0	0	0	0	0	0	ch2_1p8v det	0	0	0
37h	Page 1	ch3_iod_d iv[2]	ch3_iod_d iv[1]	ch3_iod_d iv[0]	0	0	0	0	0	0	0	0	0	1	0	0	0
38h	Page 1	ch3_outbu f_ctrl[0]	ch3_mux[1]	ch3_mux[0]	ch3_iod_ mux[1]	ch3_iod_ mux[0]	ch3_iod_d iv[13]	ch3_iod_d iv[12]	ch3_iod_d iv[11]	ch3_iod_d iv[10]	ch3_iod_d iv[9]	ch3_iod_d iv[8]	ch3_iod_d iv[7]	ch3_iod_d iv[6]	ch3_iod_d iv[5]	ch3_iod_d iv[4]	ch3_iod_d iv[3]
39h	Page 1	0	0	0	ch3_glitchl ess_en	ch3_sync _delay[4]	ch3_sync _delay[3]	ch3_sync _delay[2]	ch3_sync _delay[1]	ch3_sync _delay[0]	ch3_sync _en	ch3_mute _sel	ch3_mute	ch3_cmos _pol[1]	ch3_cmos _pol[0]	ch3_outbu f_ctrl[2]	ch3_outbu f_ctrl[1]
3Ah	Page 1	0	0	0	0	0	0	0	0	0	0	ch3_1p8v det	1	0	0	1	1

100



Table 10-61. EEPROM, Page 1 (continued)

										•							
WORD NO.	SECTION	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
3Bh	Page 1	ch4_iod_d iv[0]	0	0	0	0	0	0	0	0	0	1	0	0	0	0	0
3Ch	Page 1	ch4_mux[0]	ch4_iod_ mux[1]	ch4_iod_ mux[0]	ch4_iod_d iv[13]	ch4_iod_d iv[12]	ch4_iod_d iv[11]	ch4_iod_d iv[10]	ch4_iod_d iv[9]	ch4_iod_d iv[8]	ch4_iod_d iv[7]	ch4_iod_d iv[6]	ch4_iod_d iv[5]	ch4_iod_d iv[4]	ch4_iod_d iv[3]	ch4_iod_d iv[2]	ch4_iod_d iv[1]
3Dh	Page 1	0	ch4_glitchl ess_en	ch4_sync _delay[4]	ch4_sync _delay[3]	ch4_sync _delay[2]	ch4_sync _delay[1]	ch4_sync _delay[0]	ch4_sync _en	ch4_mute _sel	ch4_mute	0	0	ch4_outbu f_ctrl[2]	ch4_outbu f_ctrl[1]	ch4_outbu f_ctrl[0]	ch4_mux[1]
3Eh	Page 1	0	0	1	1	pll_en_cp	ch0_lvcm os_drv[1]	ch0_lvcm os_drv[0]	1	ch4_1p8v det	1	0	0	1	0	1	0
3Fh	Page 1	1	1	0	0	1	0	0	1	0	1	1	0	0	1	0	0

11 Device and Documentation Support

11.1 Device Support

11.1.1 Development Support

Contact your TI representative for more information.

11.1.2 Device Nomenclature

CDCI6214 - 62= clock generator 1= 1x PLL 4=4x outputs I = individual output enables

11.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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11.4 Trademarks

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11.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

12 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision E (October 2019) to Revision F (January 2024)	Page
•	Updated the numbering format for tables, figures, and cross-references throughout the document	1
•	Changed all instances of legacy terminology to controller and target where I ² C is mentioned	1
•	Changed Power supply ramp footnote in the <i>Timing Characteristics</i> table	10
•	Added additional details on VDD instability and instruction to set recal bit to a '1' to recalibrate the PLL.	43
•	Updated references of chx_lvds_cmtrim_inc = 2 to chx_lvds_cmtrim_inc = 0	46



•	Removed Output Channel Divider Types and Delay table	21
•	Removed the FOD control bits in the <i>Power Management</i> graphic	
•	Added Page-mode EEPROM read instructions	29
•	Changed Pre-Configured EEPROM Page 0 graphic	31
•	Changed Pre-Configured EEPROM Page 1 graphic	31
•	Added additional details on pullup resistor and load capacitor added to power-up sequence	43
•	Removed fractional output divider information from the registers	
•	Removed FOD information from the CDCI6214 Registers table	
C	changes from Revision C (November 2018) to Revision D (June 2019)	Page
•	Added VDDREF and tablenote to the output supply voltage parameter in the Recommended Operation	ing
	Conditions	
•	Added statement on chX_1p8vdet setting	
•	Changed CDCI6214 - Pre-Configured EEPROM Page 0 graphic	31
C	changes from Revision B (April 2018) to Revision C (November 2018)	Page
•	Changed pin names for pins 1 and 2 from: XIN and XOUT to: XOUT/FB_P and XIN/FB_N	
•	Changed descriptions for pins 1 and 2	
•	Changed pin names for pins 1 and 2 in Absolute Maximum Ratings	5
•	Changed pin names for pins 1 and 2 in Reference Input, Single-Ended and Differential Mode Character (REFP, REFN, FB_P, FB_N)	
•	Changed Input capacitance specification symbols in Reference Input, Single-Ended and Differential	Mode
	Characteristics (REFP, REFN, FB_P, FB_N) from: C _{IN_XOUT} and C _{IN_XIN} to: C _{IN_XOUT/FB_P} and C _{IN_XI} Changed pins 1 and 2 from: XIN and XOUT to: XOUT/FB_P and XIN/FB_N in the Functional Block L	
	Changed pine 1 and 2 from: Any and According to According to an axing to Broad	-
	Changed pins 1 and 2 from: XIN and XOUT to: XOUT/FB_P and XIN/FB_N in the <i>Reference Block</i> of	
	Changed External (XIN) pin to: FB_P/N in the <i>Phase-Locked Loop Circuit</i> graphic	
	Changed pins 1 and 2 from: XIN and XOUT to: XOUT/FB_P and XIN/FB_N in the CDC/6214 - Pre-	
	Configured EEPROM Page 0 and CDCI6214 - Pre-Configured EEPROM Page 1 graphics	31
	Changed pins XIN and XOUT to: XOUT/FB_P and XIN/FB_N in the <i>Typical Applications</i> schematics	
	Changed design parameter superscript to a subscript	
_	Changes sough parameter supercompt to a supercompt minimum.	
C	changes from Revision A (October 2017) to Revision B (April 2018)	Page
•	Changed pinout pins 5 and 6 from NC to REFP, REFN inputs	
•	Changed supply voltage maximum from: 3.6 V to: 3.65 V	
_	Removed Skew between HCSL maximum from the Output Skew and Delay Characteristics table	10
_		_
C	changes from Revision * (July 2017) to Revision A (October 2017)	Page
•	Changed device status from Advanced Info to Production Data	
•	Changed REFSEL pin description to reflext REFMUX control.	22

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

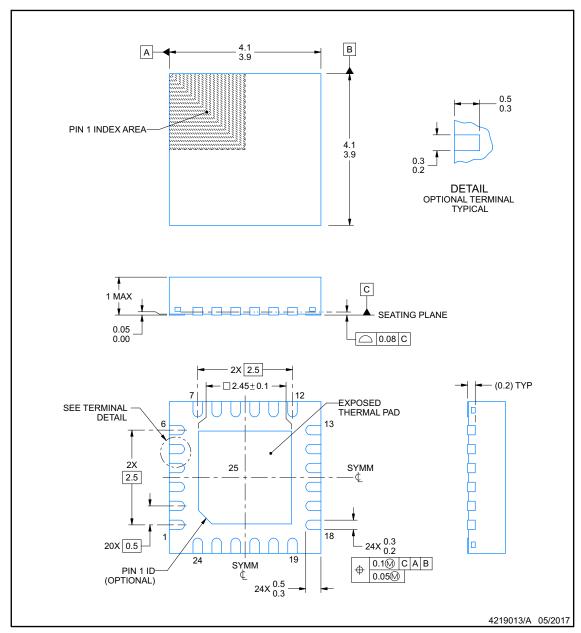


RGE0024B

PACKAGE OUTLINE

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.
 The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



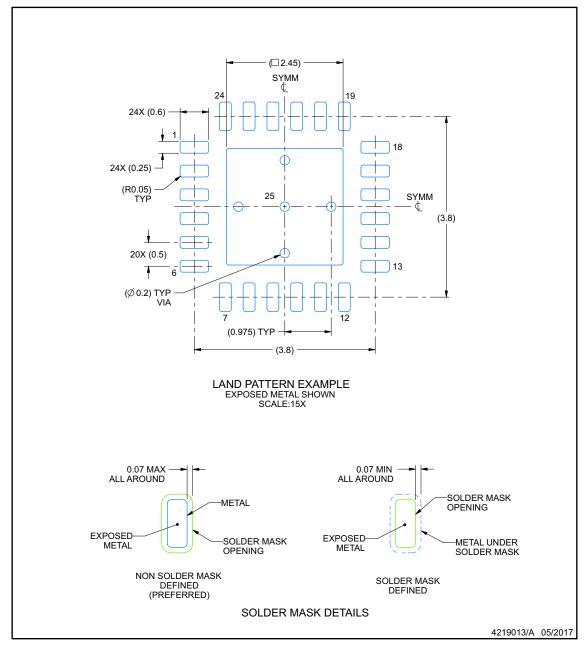


EXAMPLE BOARD LAYOUT

RGE0024B

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature
- number SLUA271 (www.ti.com/lit/slua271).

 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



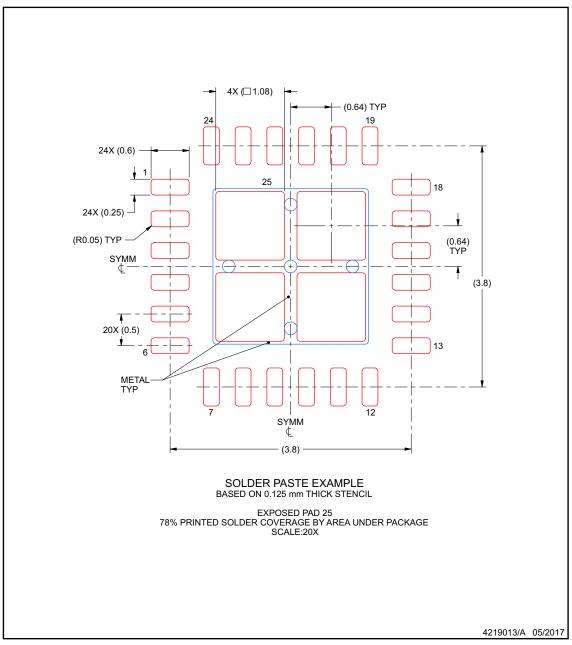


EXAMPLE STENCIL DESIGN

RGE0024B

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
	(1)	(2)			(3)	(4)	(5)		(6)
CDCI6214RGER	NRND	Production	VQFN (RGE) 24	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCI 6214A1
CDCl6214RGER.A	NRND	Production	VQFN (RGE) 24	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCI 6214A1
CDCl6214RGET	NRND	Production	VQFN (RGE) 24	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCI 6214A1
CDCI6214RGET.A	NRND	Production	VQFN (RGE) 24	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	CDCI 6214A1

⁽¹⁾ Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.



PACKAGE OPTION ADDENDUM

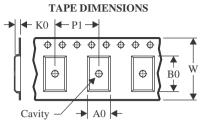
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PACKAGE MATERIALS INFORMATION

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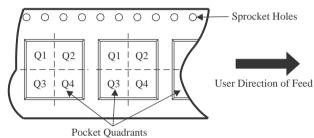
TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCI6214RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
CDCI6214RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
CDCI6214RGER	VQFN	RGE	24	3000	346.0	346.0	33.0	
CDCI6214RGET	VQFN	RGE	24	250	182.0	182.0	20.0	

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